11th International Summer School on RF MEMS and RF Microsystems
IHP, Frankfurt (Oder) – Germany June 22nd – 26th 2015

Basics of mm-wave Measurements

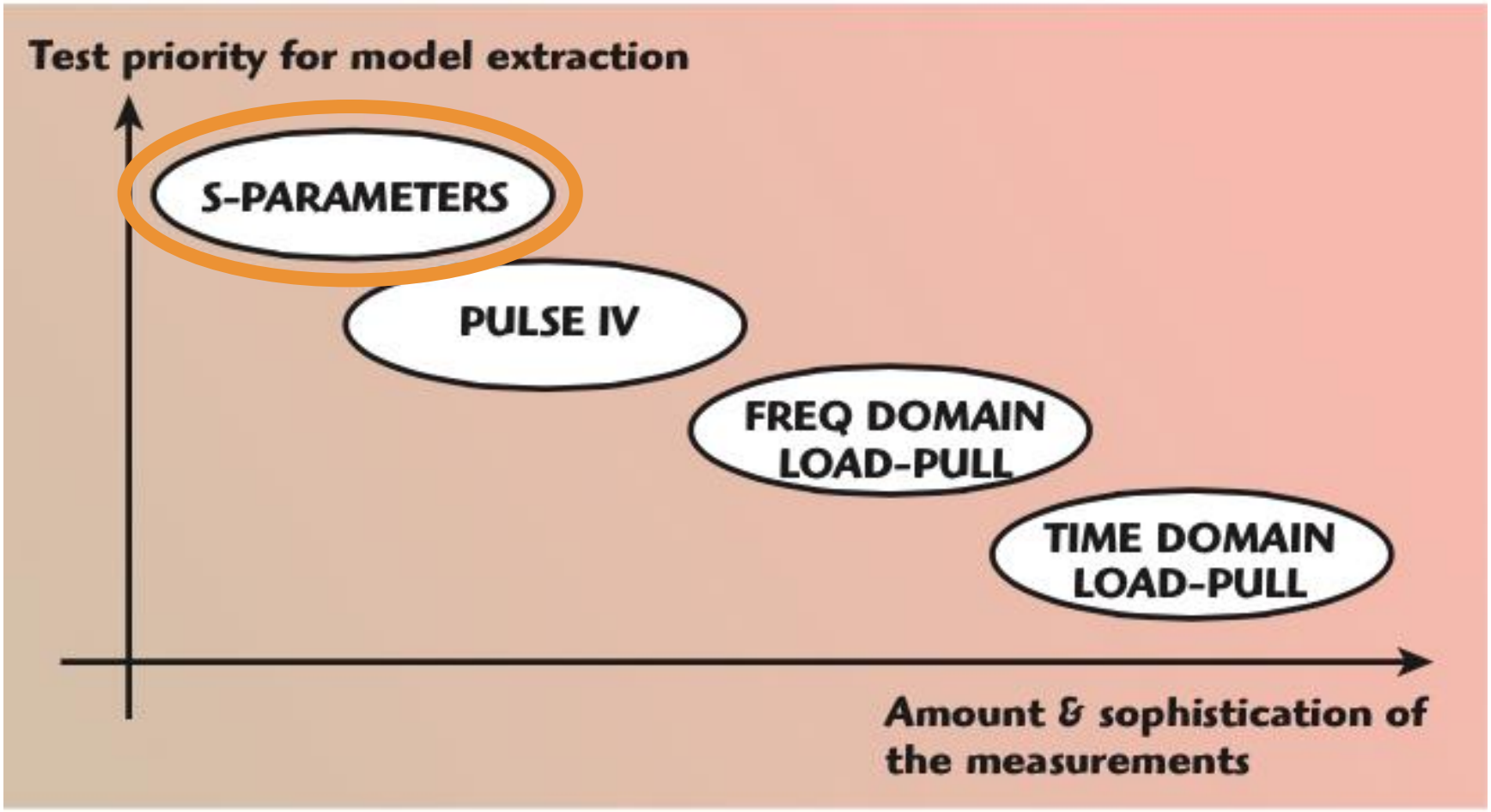
Dr. Andrej Rumiantsev

Director RF Technologies MPI Corporation

Outline

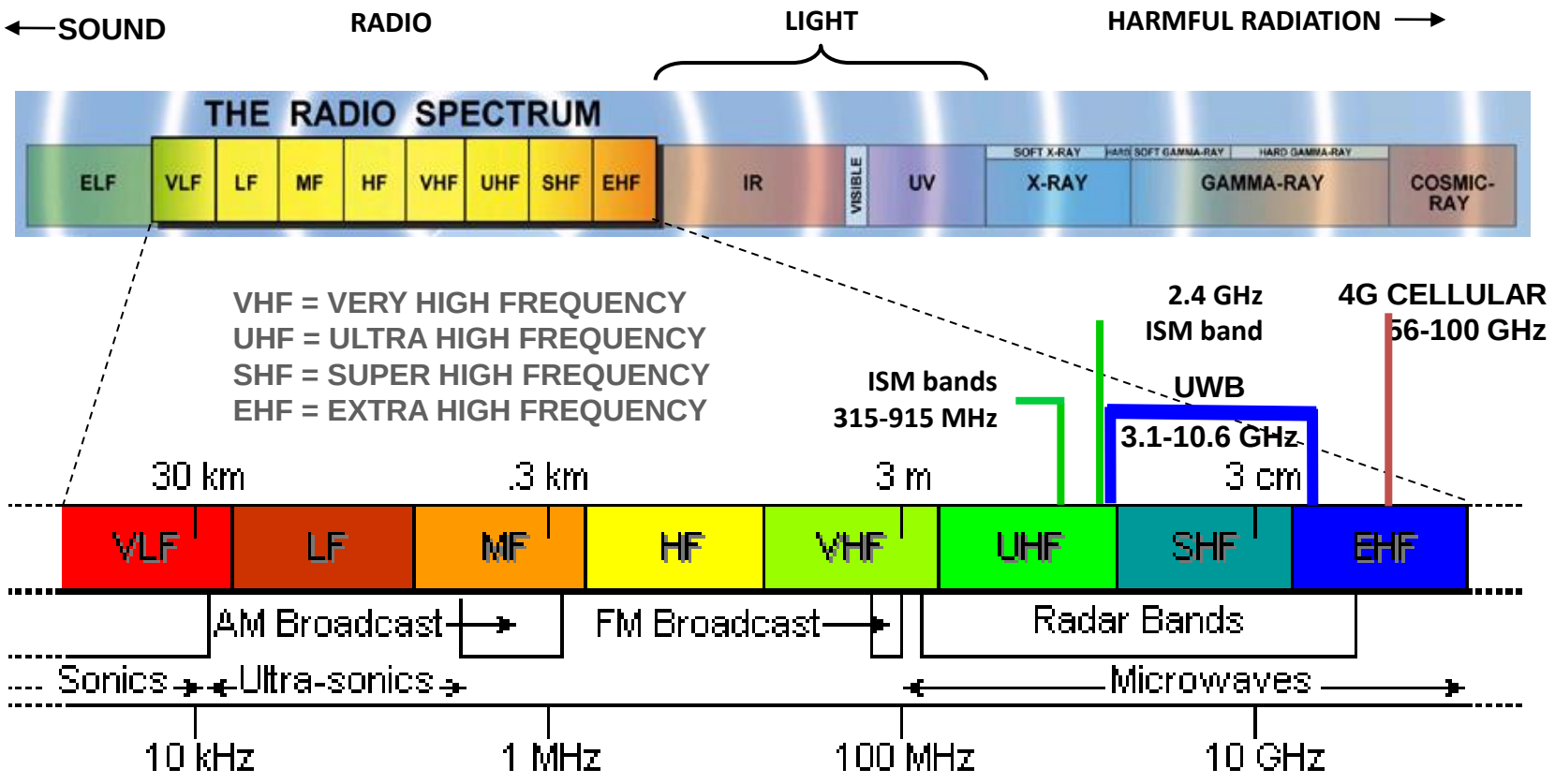
- Introduction
- S-parameters Basics
- Measurement of S-parameters
- VNA Building Blocks
- Instrumentation

Importance of RF-Measurements



T. Gasseling , MW Journal, 03-2012

Where Do RF & Microwaves Start?



10 GHz ~ 3 cm wave length

Source: JSC.MIL

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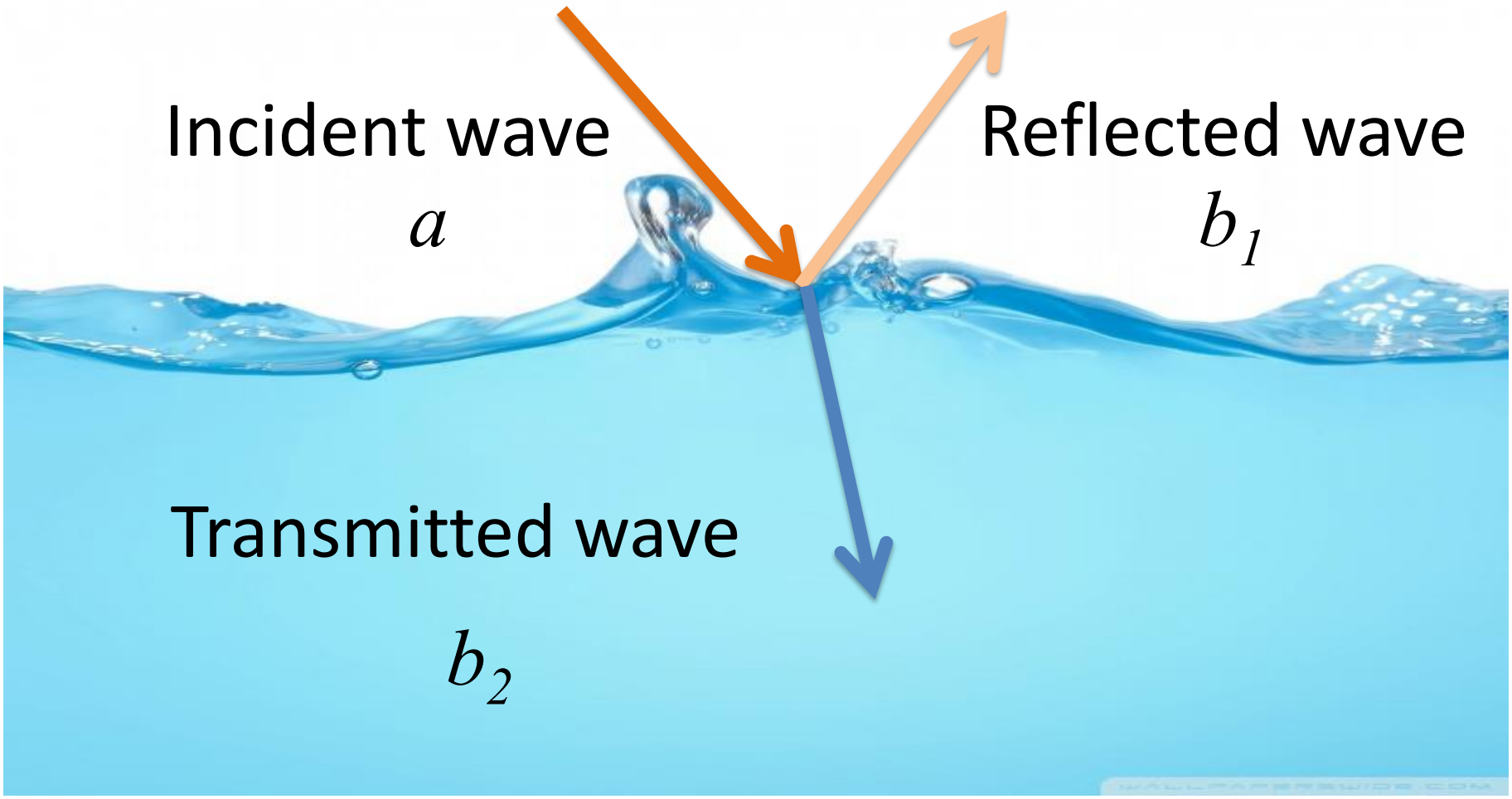
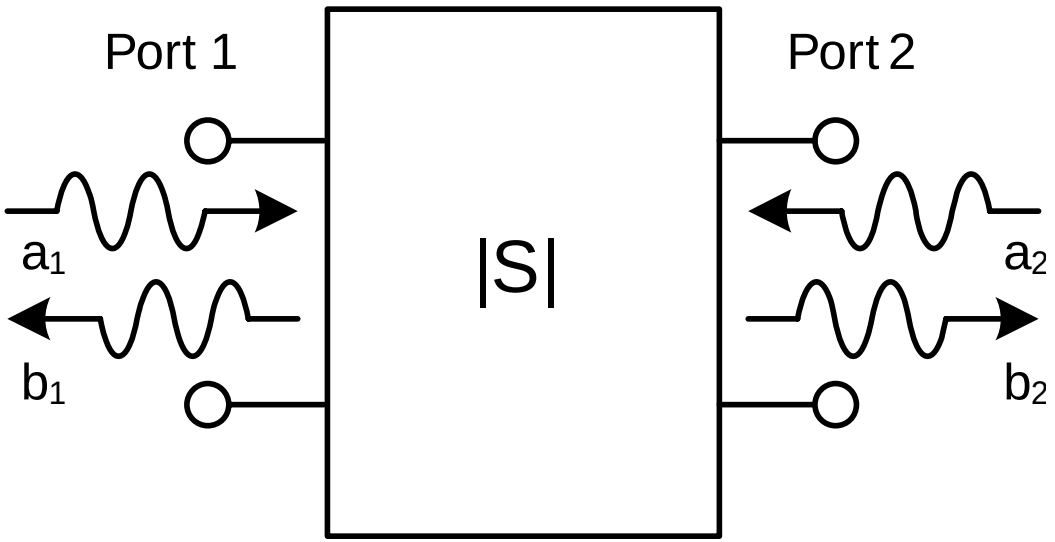
- Measurement of S-parameters
- VNA Building Blocks
- Instrumentation

..its all about Waves



… over S-Parameters

- Relationship of:
  - incident (a) and reflected/transmitted (b) waves at device terminals



Why S-Parameters

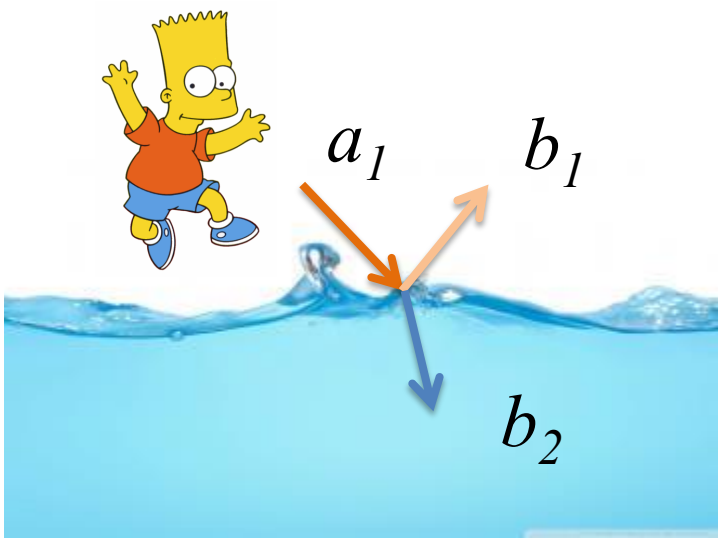
- Wave quantities are easy to measure
- Can be converted to Z-, Y-, H- and other parameters

$$S_{ii} = \frac{b_i}{a_i} = \frac{Z_{DUT} - Z_{REF}}{Z_{DUT} + Z_{REF}}$$

S-Parameter Matrix

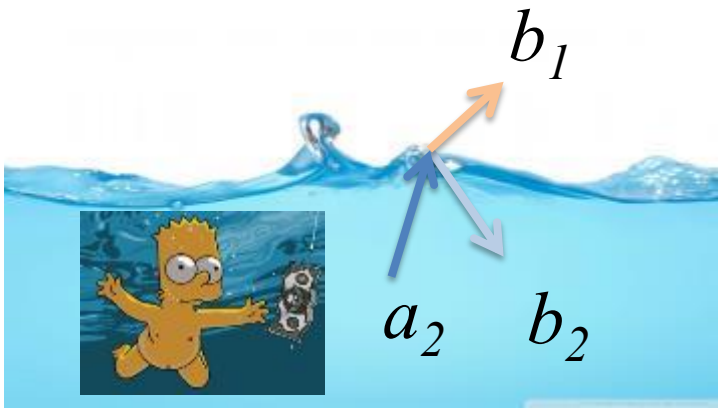
- Forward direction

$S_{11}=b_1/a_1$ $S_{21}=b_2/a_1$



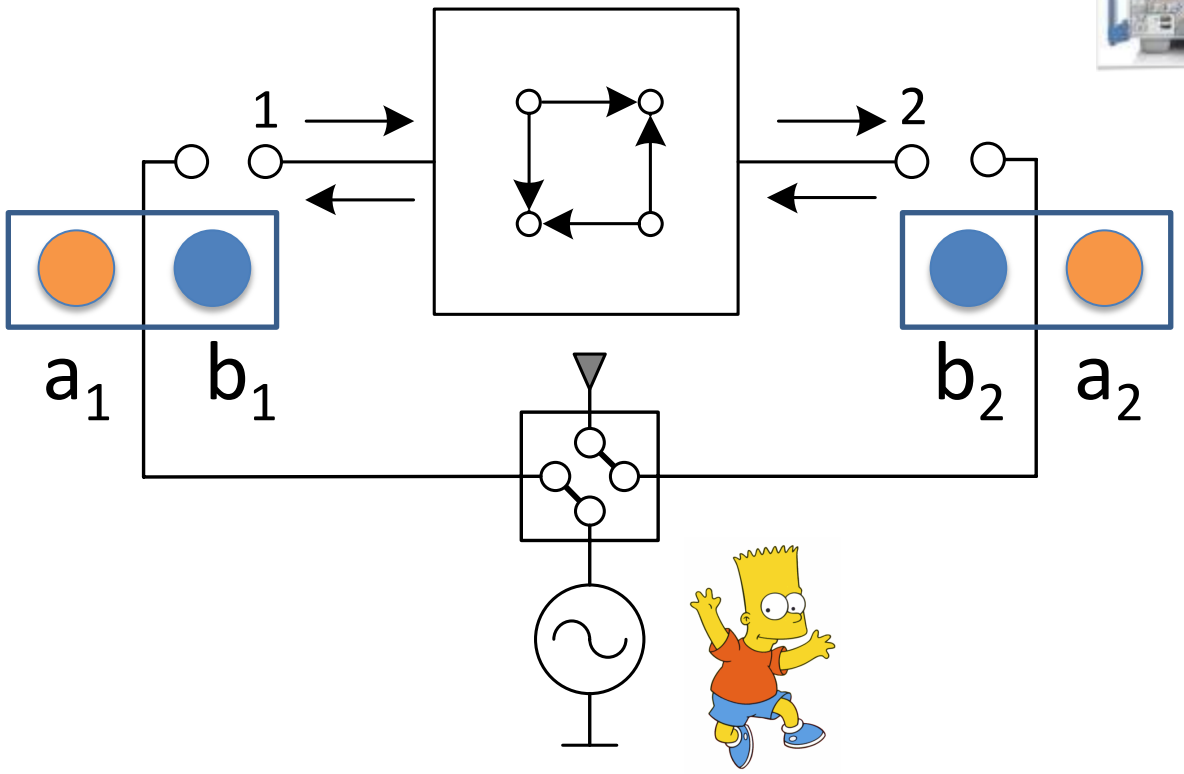
- Reverse direction

$S_{22}=b_2/a_2$ $S_{12}=b_1/a_2$



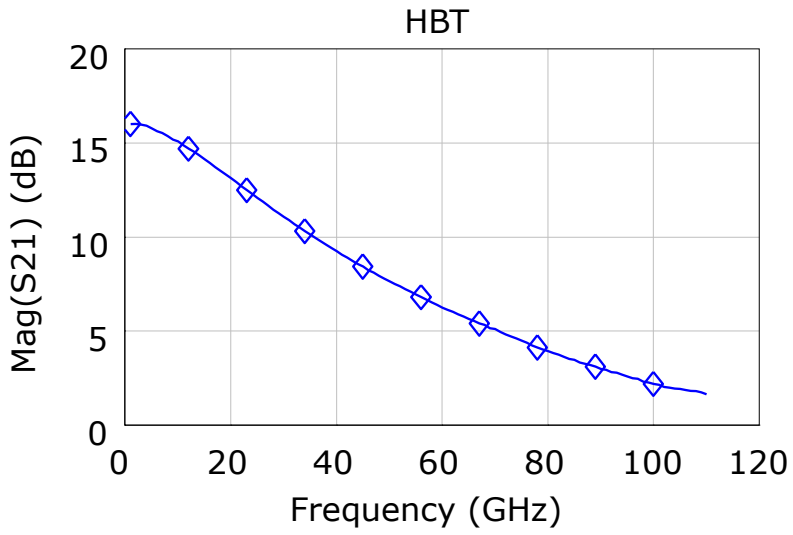
S-Parameters Measured by VNA

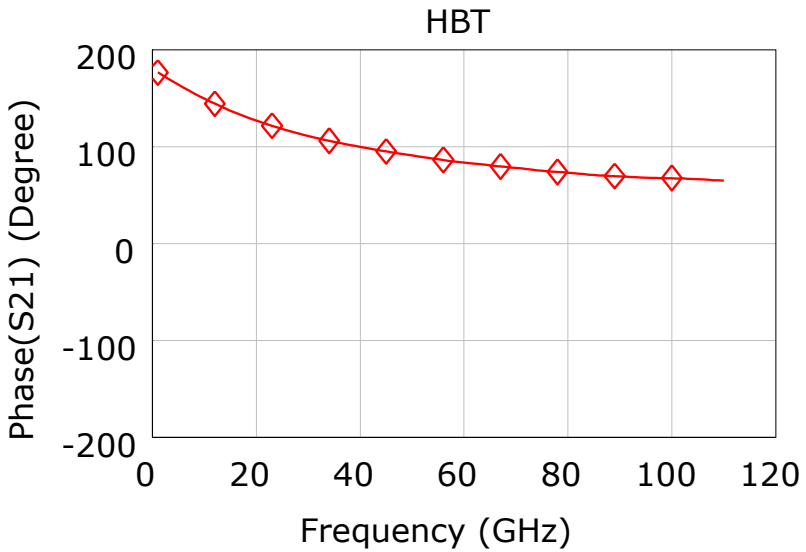
- Vector Network Analyzer (VNA)



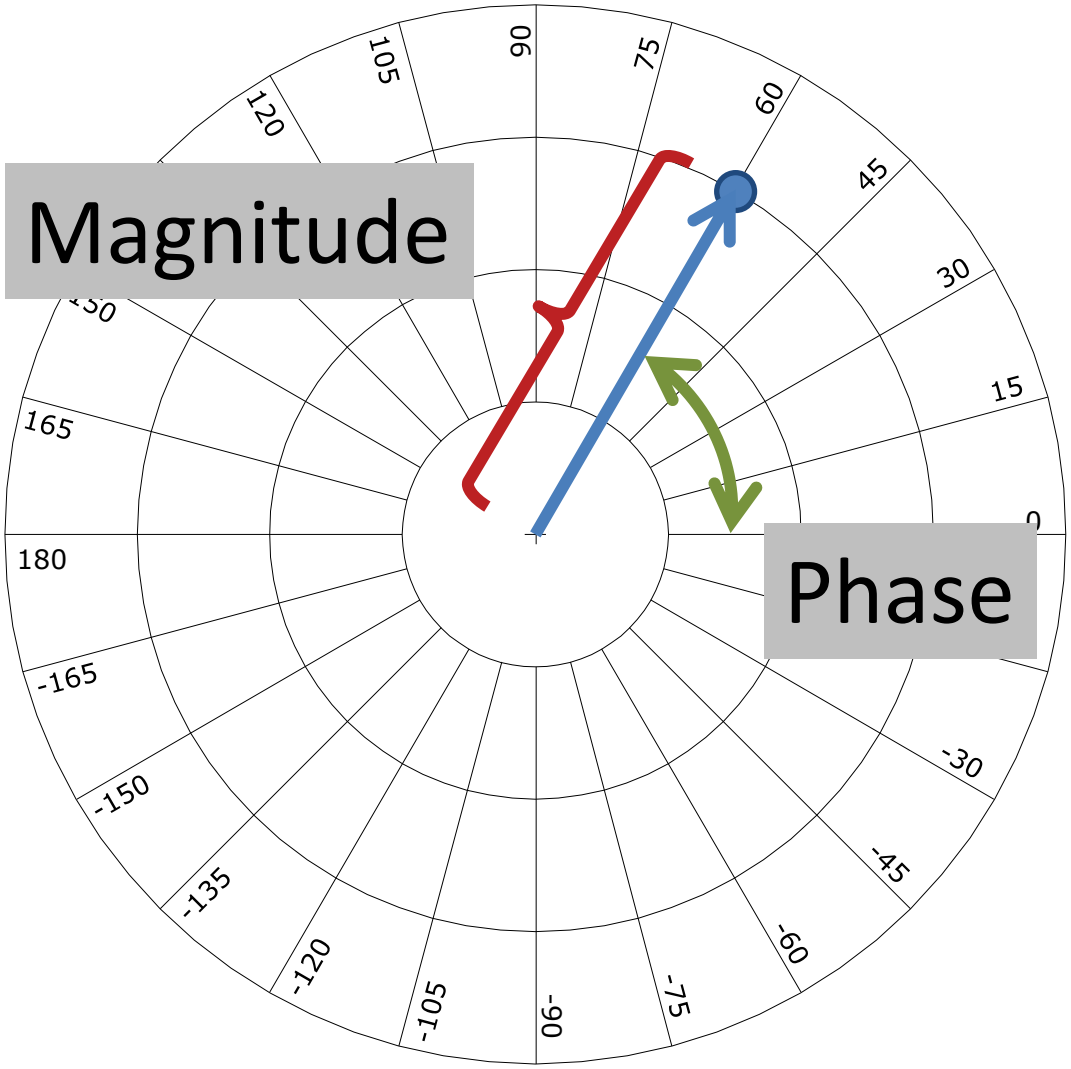
Why "Vector" ?

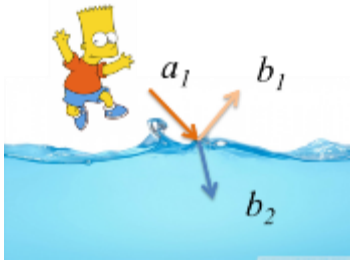
- S-parameters are complex quantities:
  - Magnitude
  - Phase



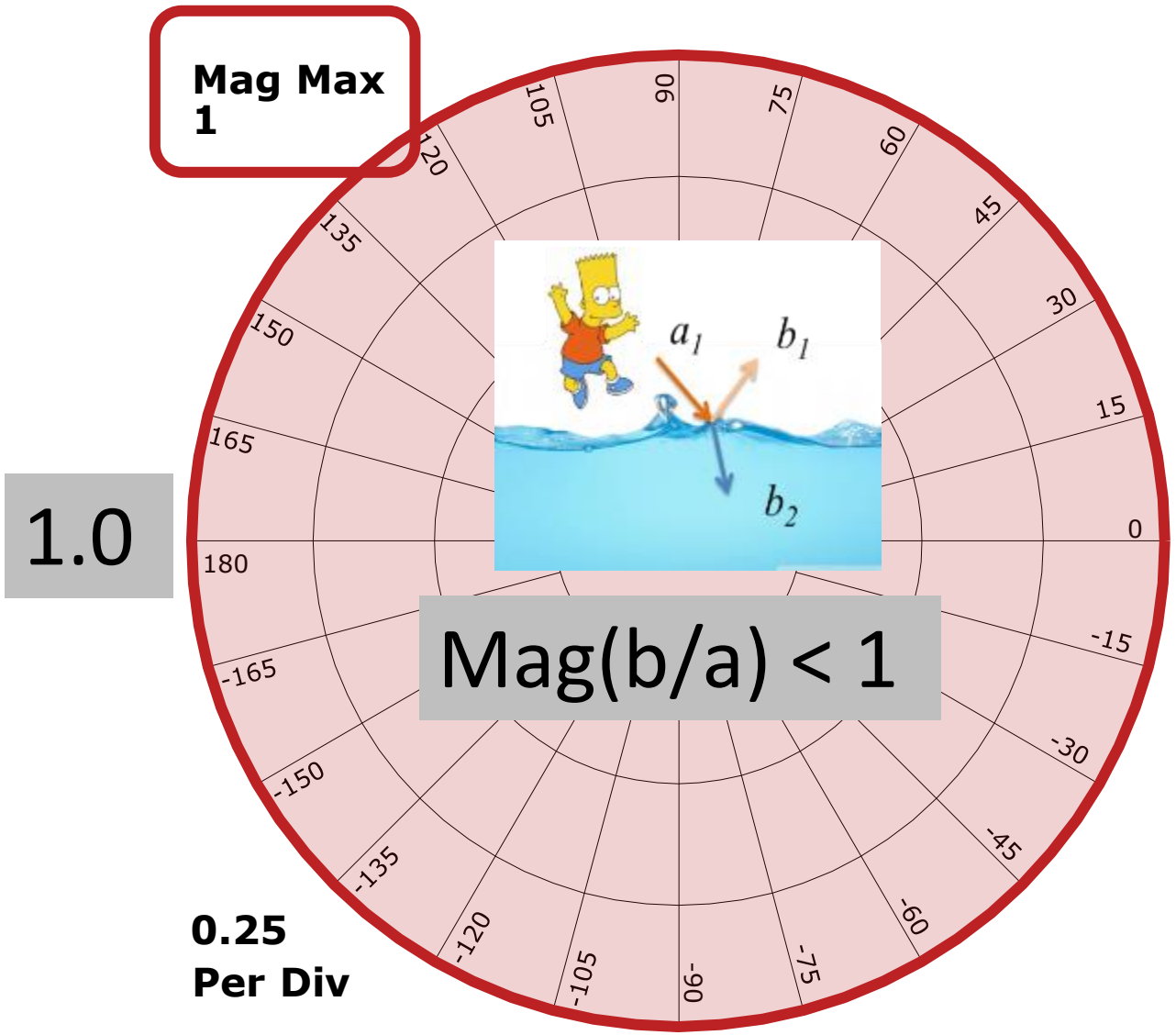


Vector on Polar Plot

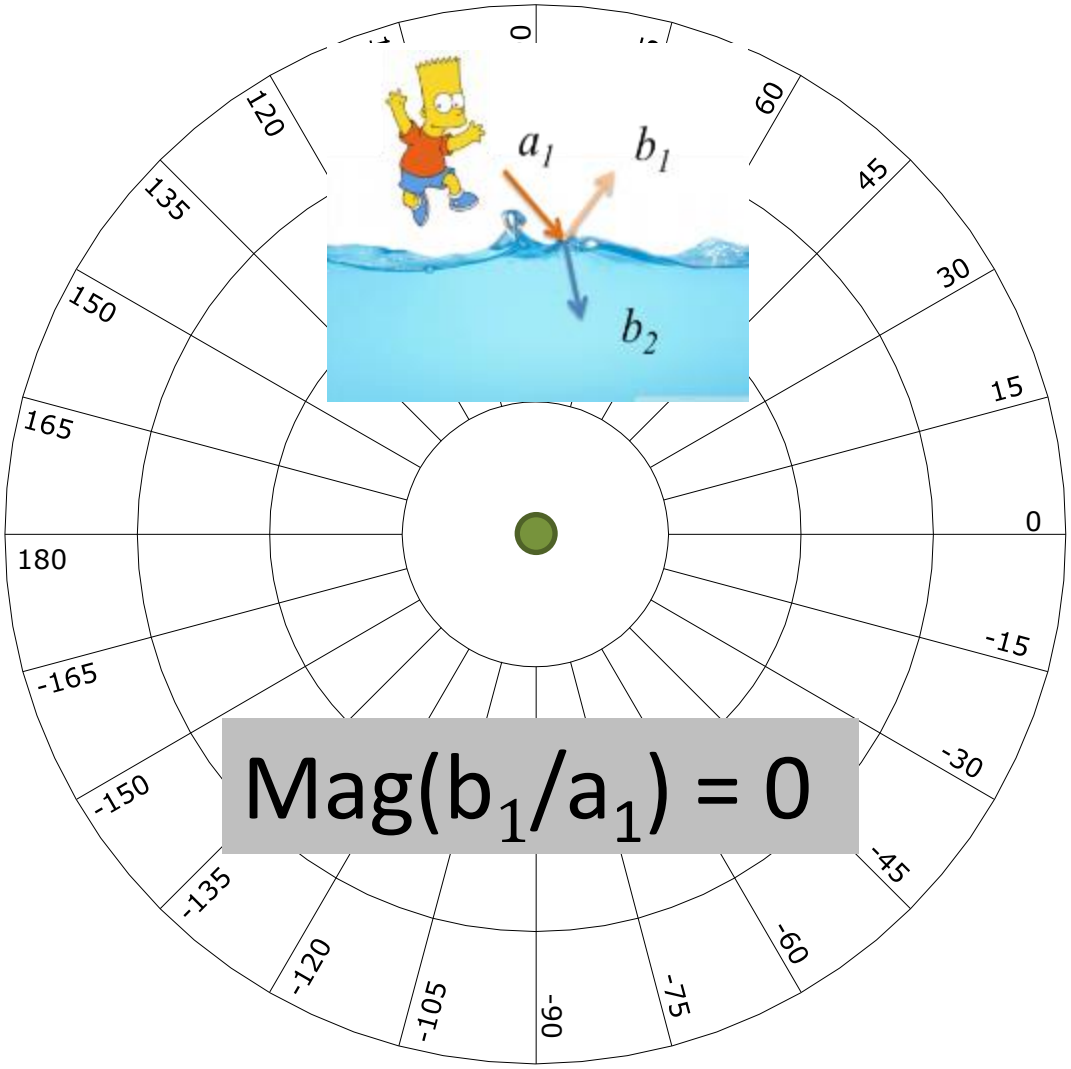




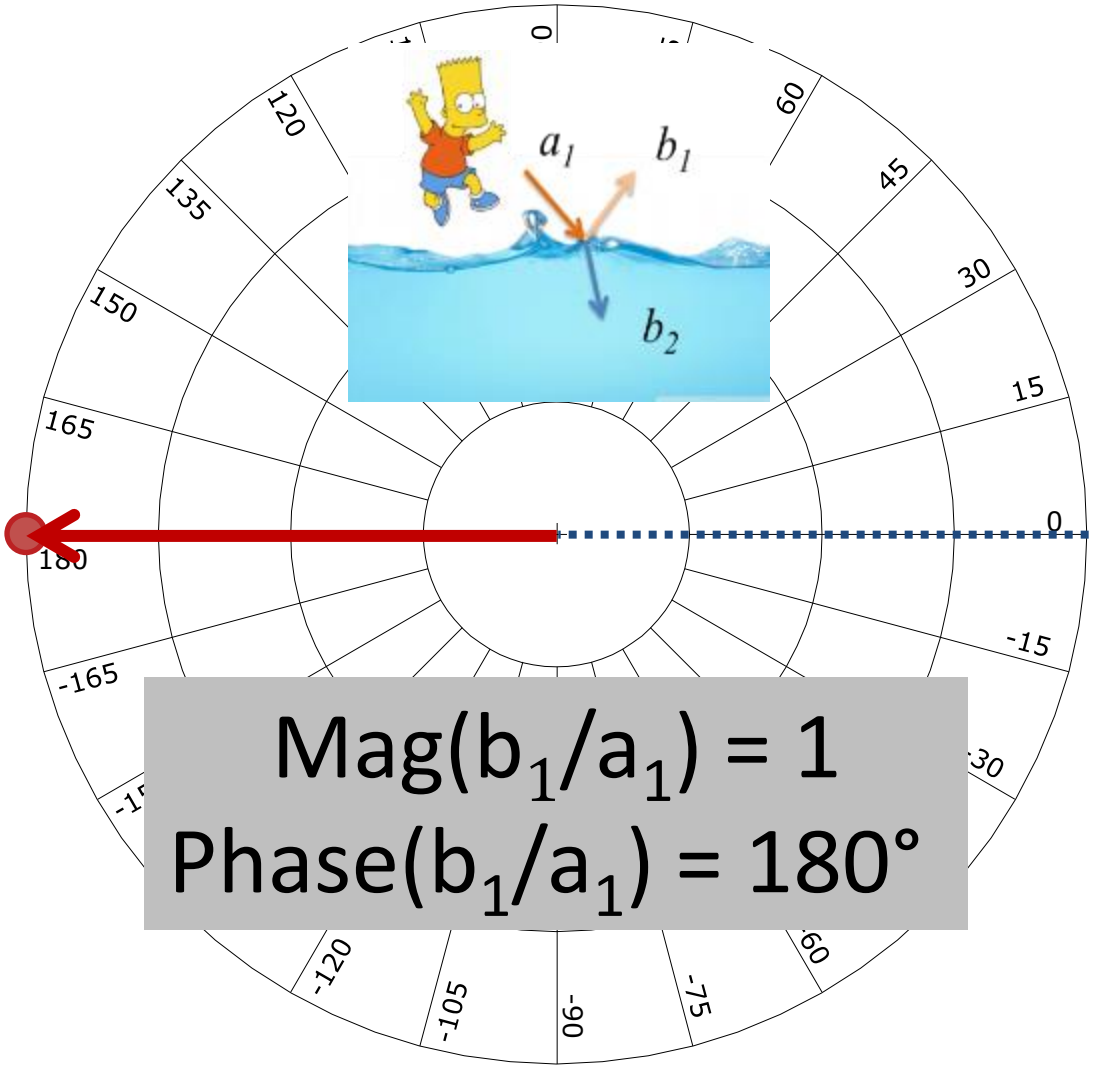
Passive Component



Match (Load)



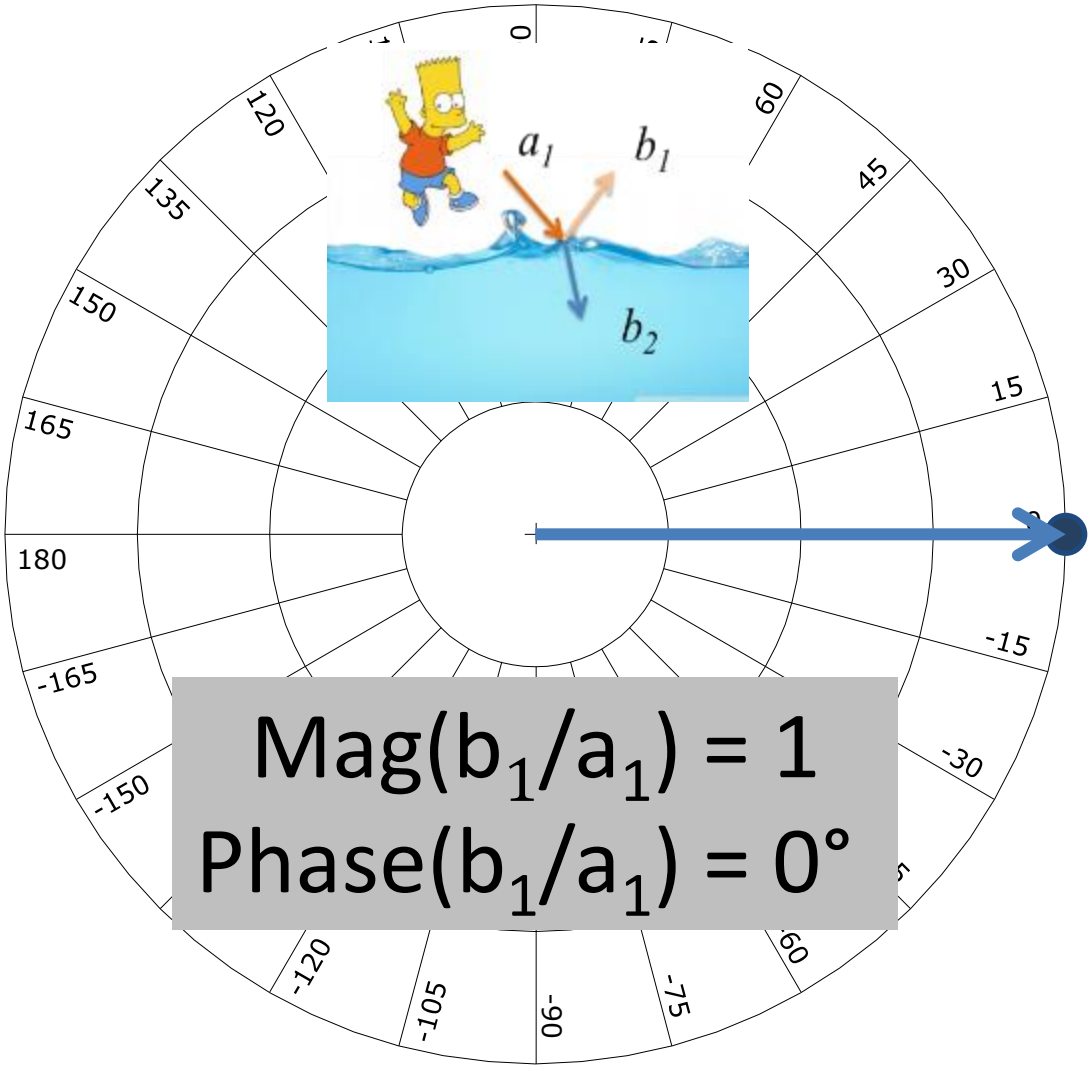
Short



$Mag(b_1/a_1) = 1$

$Phase(b_1/a_1) = 180°$

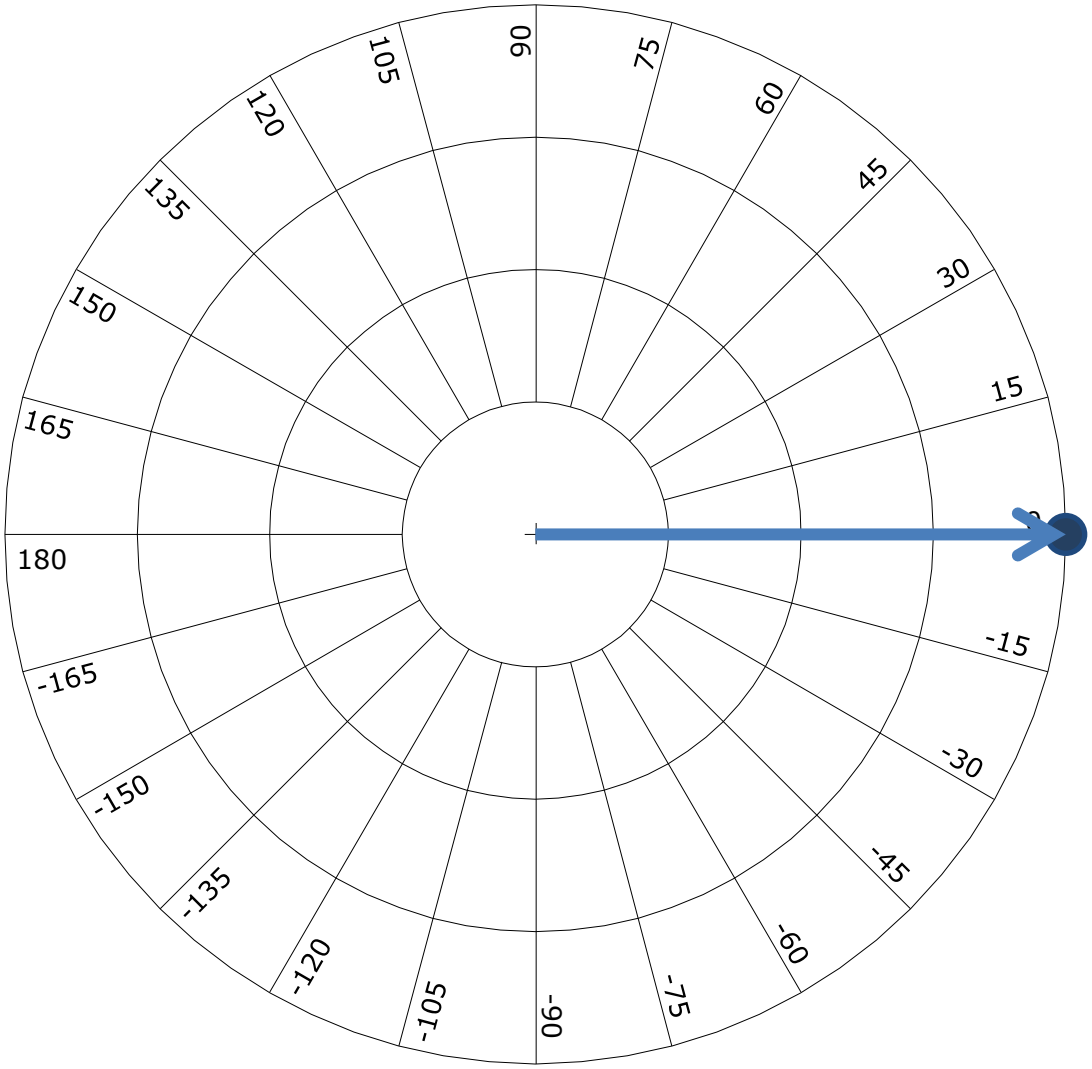
Open



$$Mag(b_1/a_1) = 1$$
$$Phase(b_1/a_1) = 0°$$

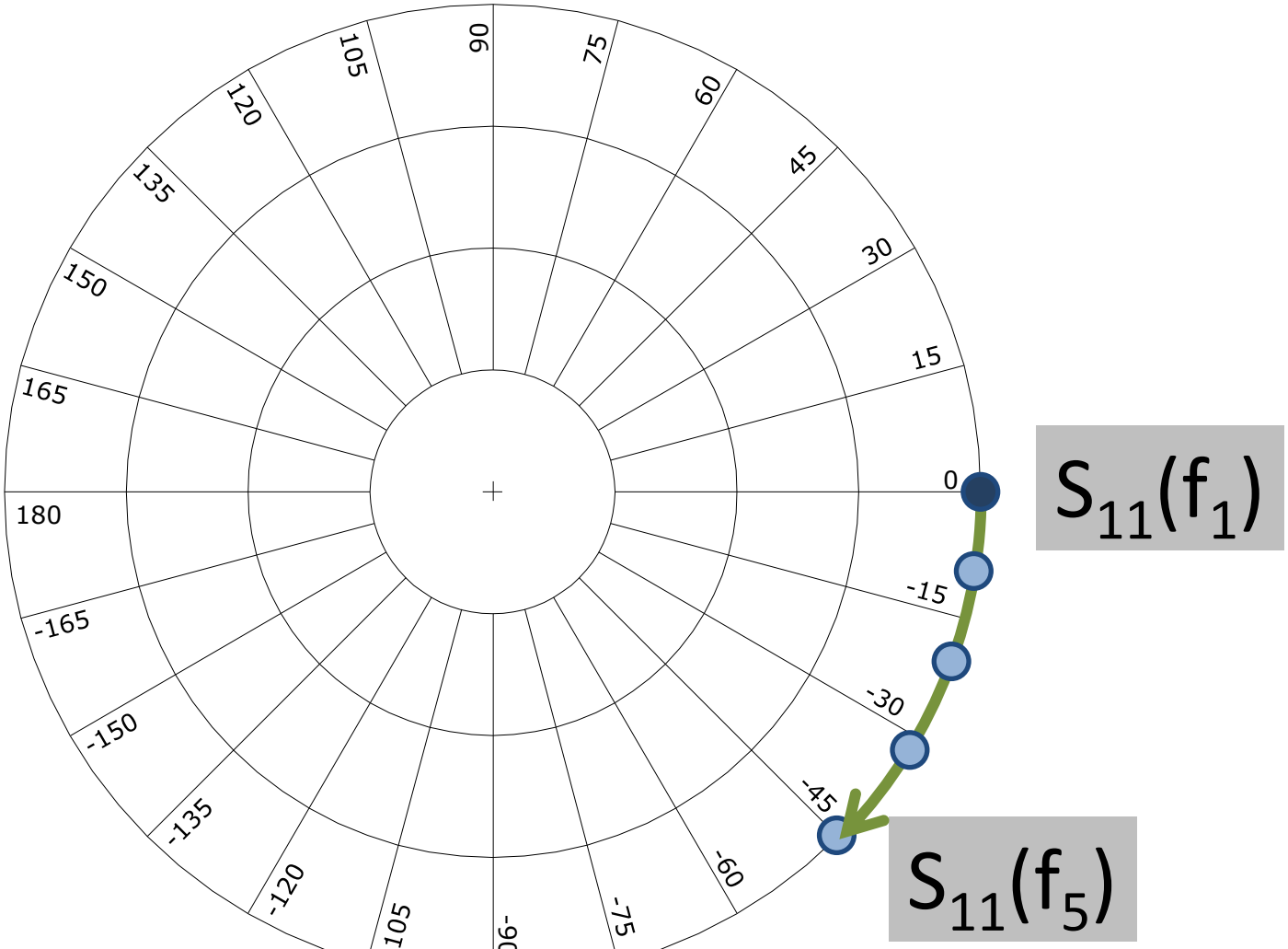
MPI

Data over Frequency

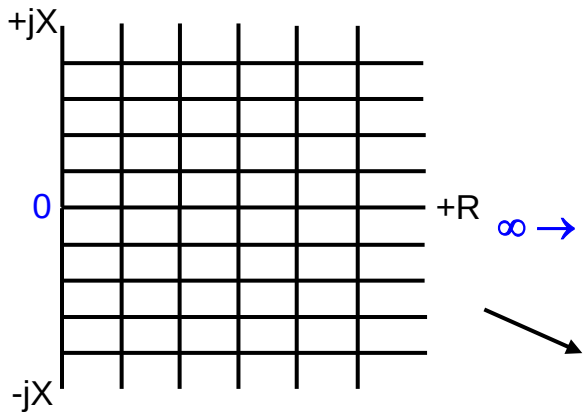


$S_{11}(f_1)$

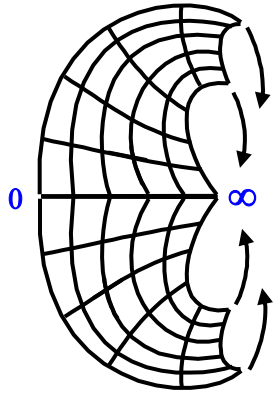
Data over Frequency

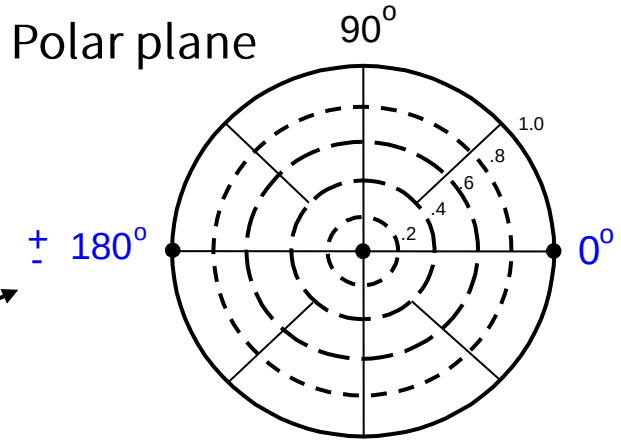


Smith Chart

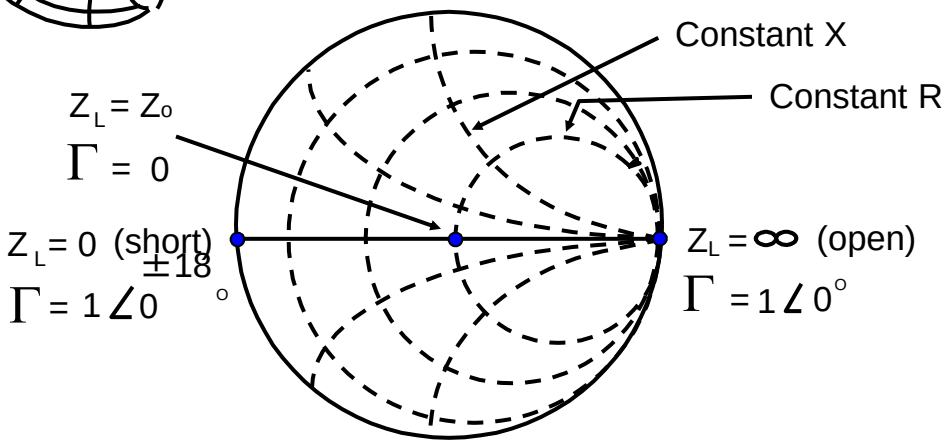


Rectilinear impedance plane





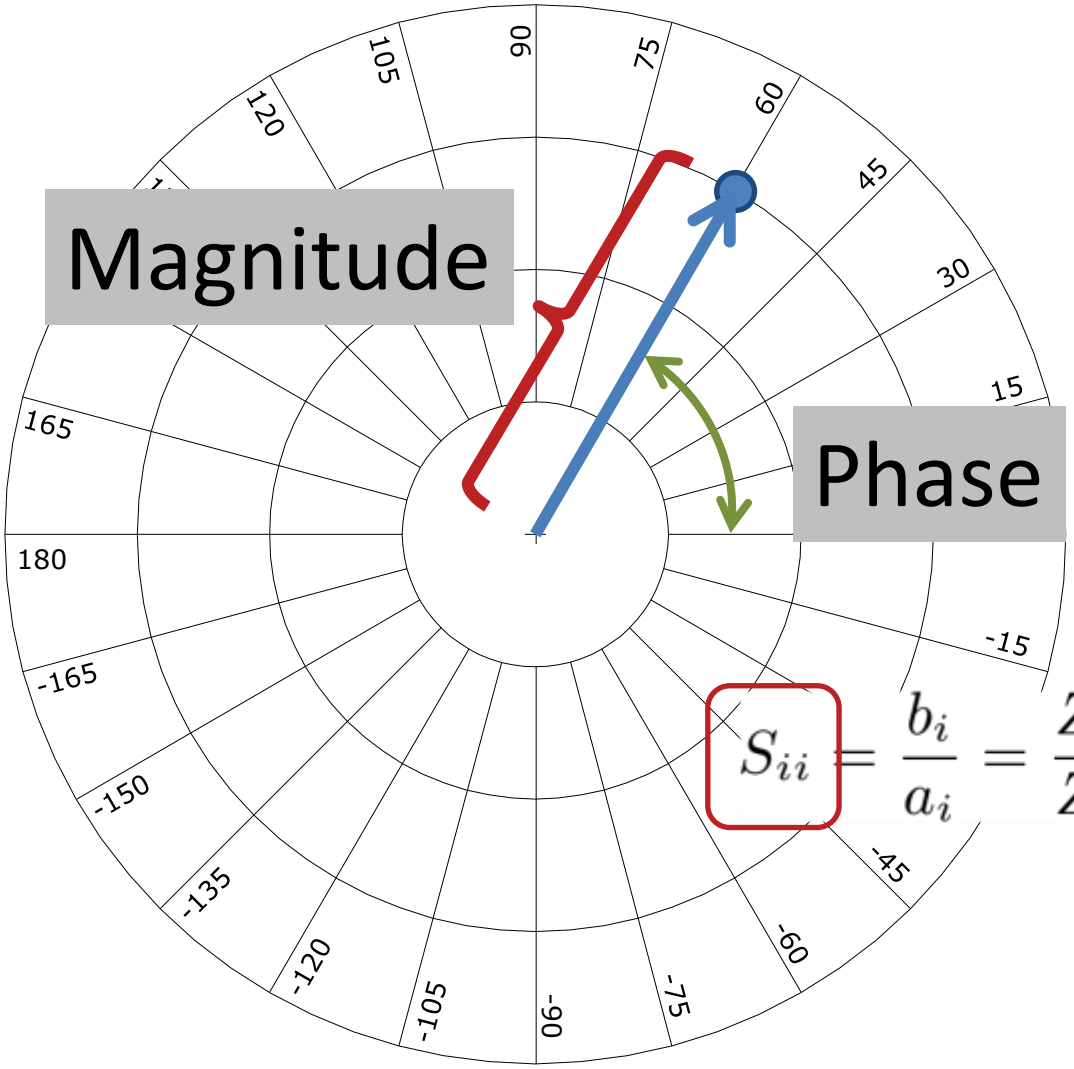
Smith Chart maps rectilinear impedance plane onto polar plane



Smith chart

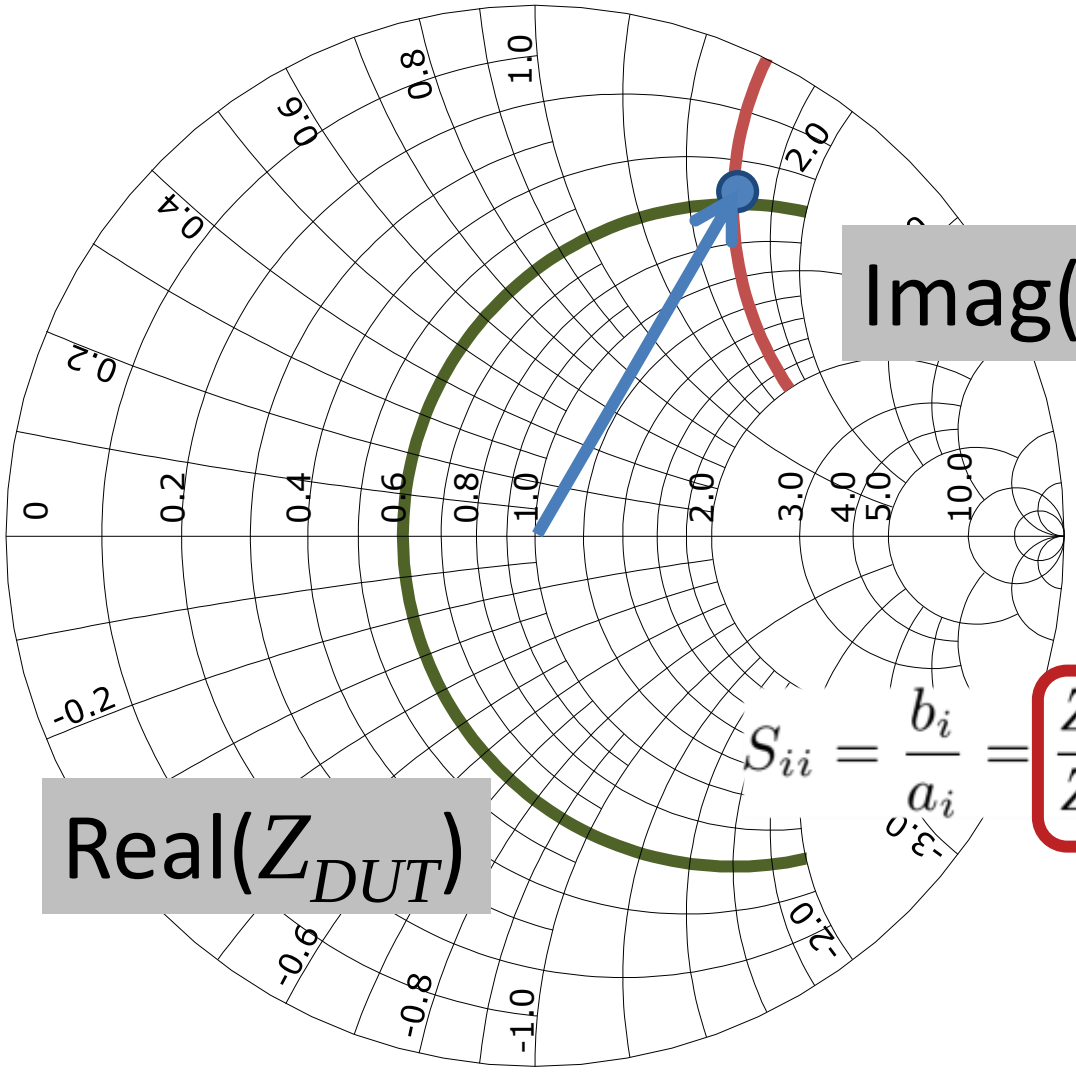
Picture source: D. Ballo Keysight

Polar Chart vs. Smith Chart



$$S_{ii} = \frac{b_i}{a_i} = \frac{Z_{DUT} - Z_{REF}}{Z_{DUT} + Z_{REF}}$$

Polar Chart vs. Smith Chart



Matching of two Media = Transparency

$Z_{0\ (AIR)}$

$Z_{0\ (WATER)}$

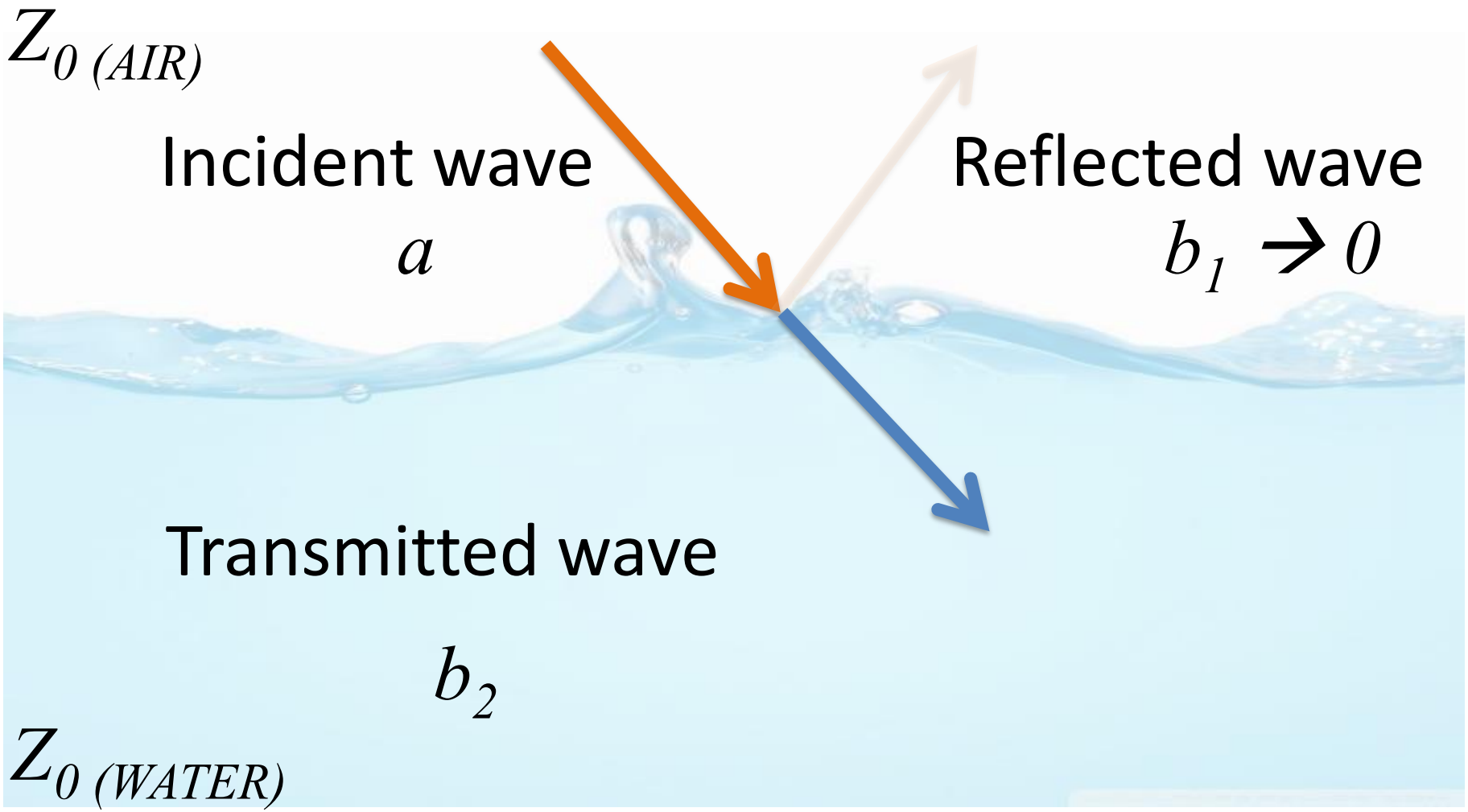
MPI

Matching of two Media = Transparency

$Z_{0\ (AIR)}$

$Z_{0\ (WATER)}$

Matching of two Media = Transparency



Matching Conditions

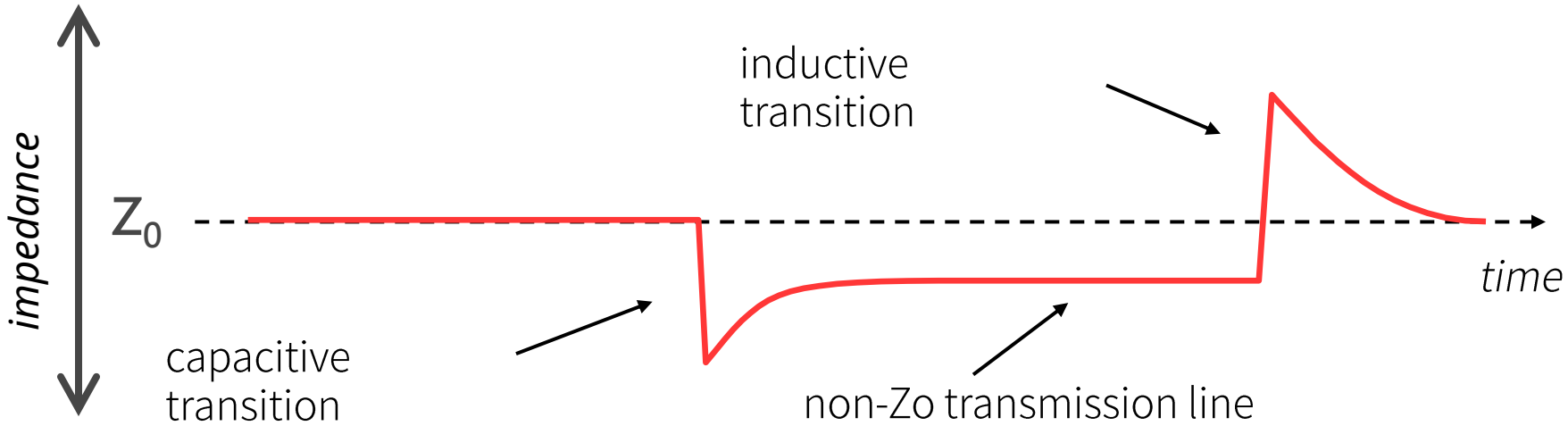
$$S_{ii} = \frac{b_i}{a_i} = \frac{Z_{DUT} - Z_{REF}}{Z_{DUT} + Z_{REF}}$$

$$b_1 \rightarrow 0 \qquad Z_{DUT} = Z_{REF} \qquad S_{ii} \rightarrow 0$$

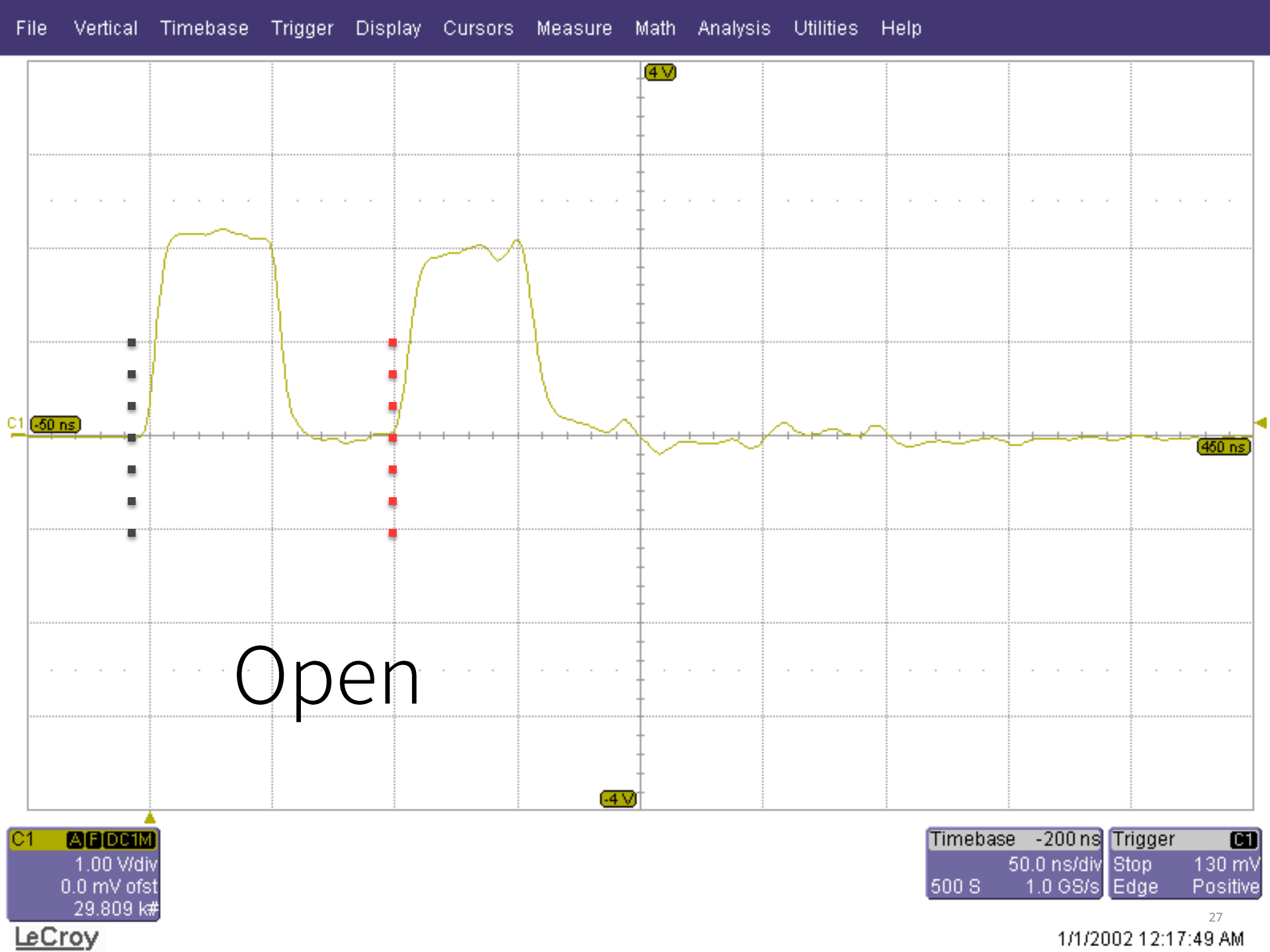
$$Z_{REF} = 50\ \Omega$$

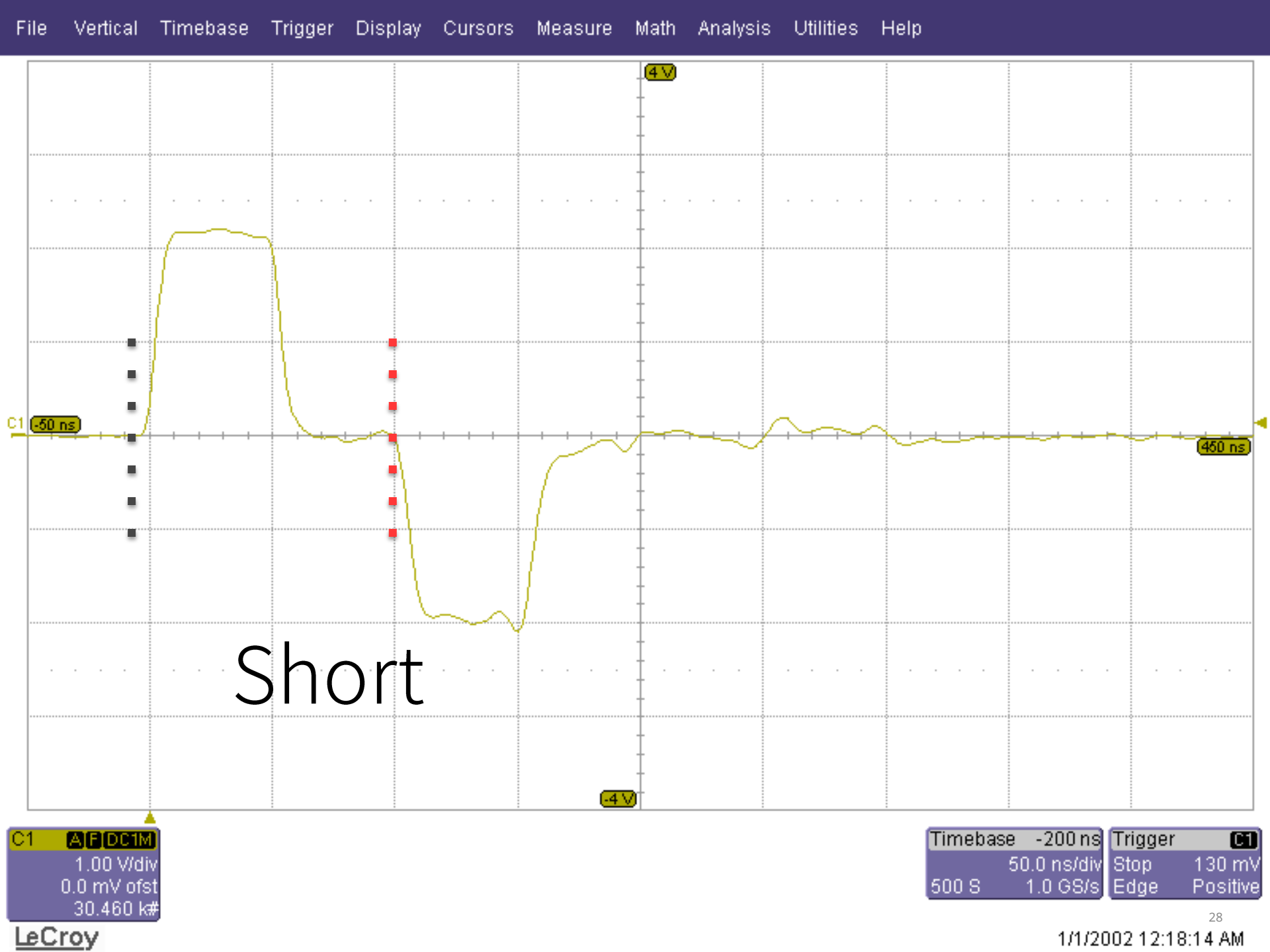
Time-Domain Reflectometry (TDR)

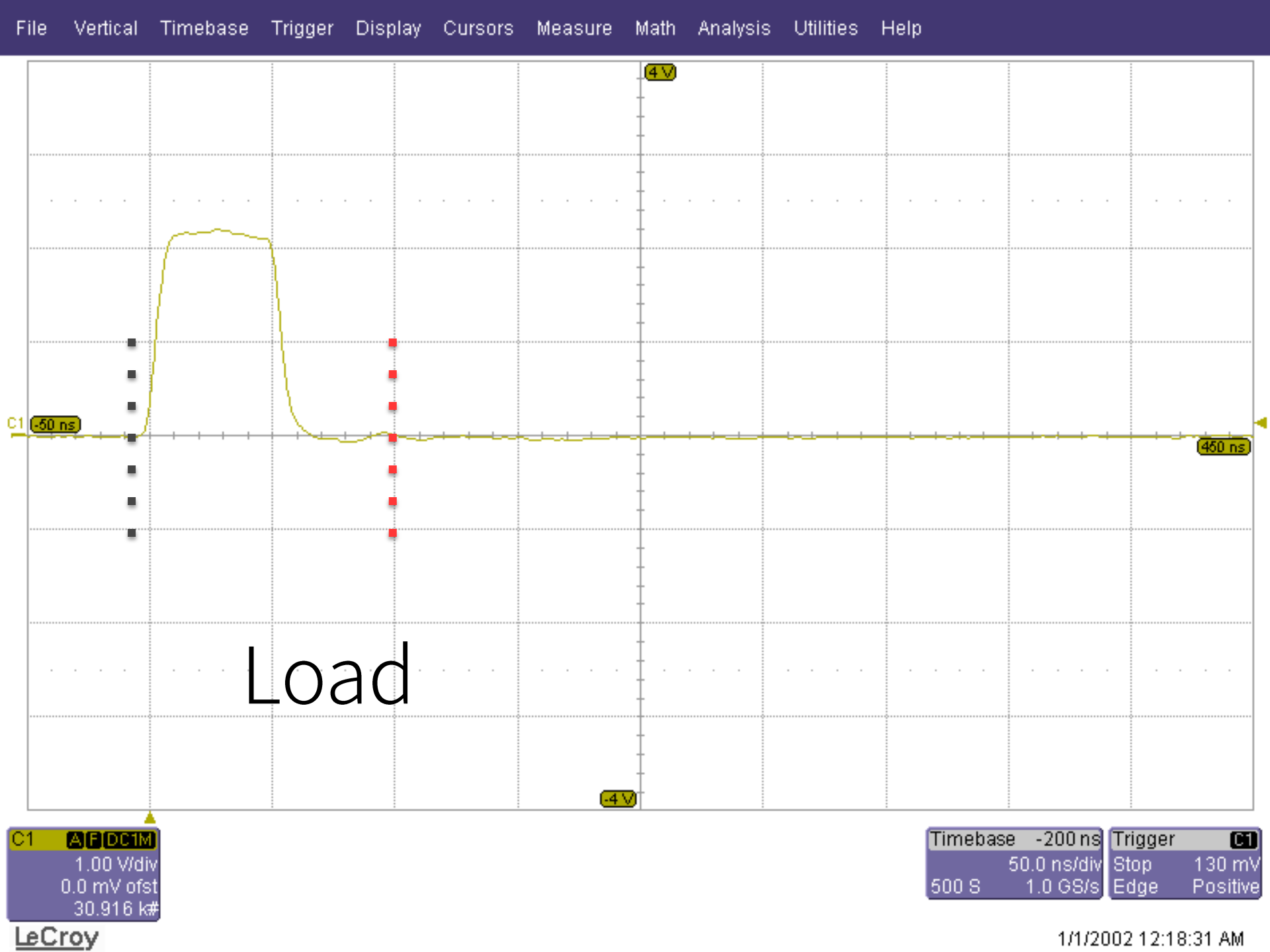
- Analyze impedance versus time
- Distinguish between inductive and capacitive transitions



Picture source: D. Ballo Keysight


File Vertical Timebase Trigger Display Cursors Measure Math Analysis Utilities Help
4 V
C1
-50 ns
450 ns
-4 V
Open
C1 A F DC1M
1.00 V/div
0.0 mV ofst
29.809 k#
Timebase -200 ns
50.0 ns/div
500 S 1.0 GS/s
Trigger C1
Stop 130 mV
Edge Positive
LeCroy
1/1/2002 12:17:49 AM


File Vertical Timebase Trigger Display Cursors Measure Math Analysis Utilities Help
4 V
C1
-50 ns
450 ns
-4 V
Short
C1 A F DC1M
1.00 V/div
0.0 mV ofst
30.460 k#
Timebase -200 ns
50.0 ns/div
500 S 1.0 GS/s
Trigger C1
Stop 130 mV
Edge Positive
LeCroy
1/1/2002 12:18:14 AM


File Vertical Timebase Trigger Display Cursors Measure Math Analysis Utilities Help
4 V
C1
-50 ns
450 ns
Load
-4 V
C1 A F DC1M
1.00 V/div
0.0 mV ofst
30.916 k#
Timebase -200 ns
50.0 ns/div
500 S 1.0 GS/s
Trigger C1
Stop 130 mV
Edge Positive
LeCroy
1/1/2002 12:18:31 AM

Outline

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- S-parameters Basics
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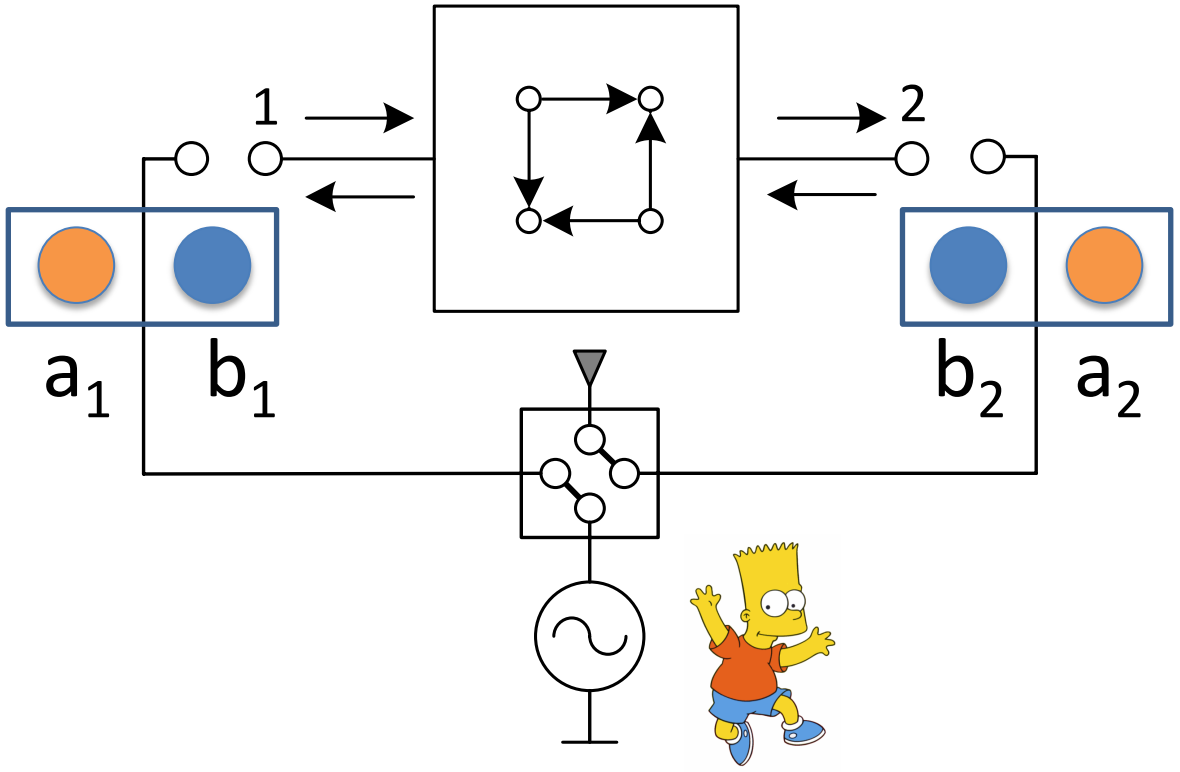
- VNA Building Blocks
- Instrumentation

Vector Network Analyzer

Device Under Test (DUT)



At the early days…

- Dr. Rohde and Dr. Schwarz first commercial product for RF measurement: 1933
- Z-g Graph from Rohde & Schwarz, early 50s

End of 60s…70s…80s…

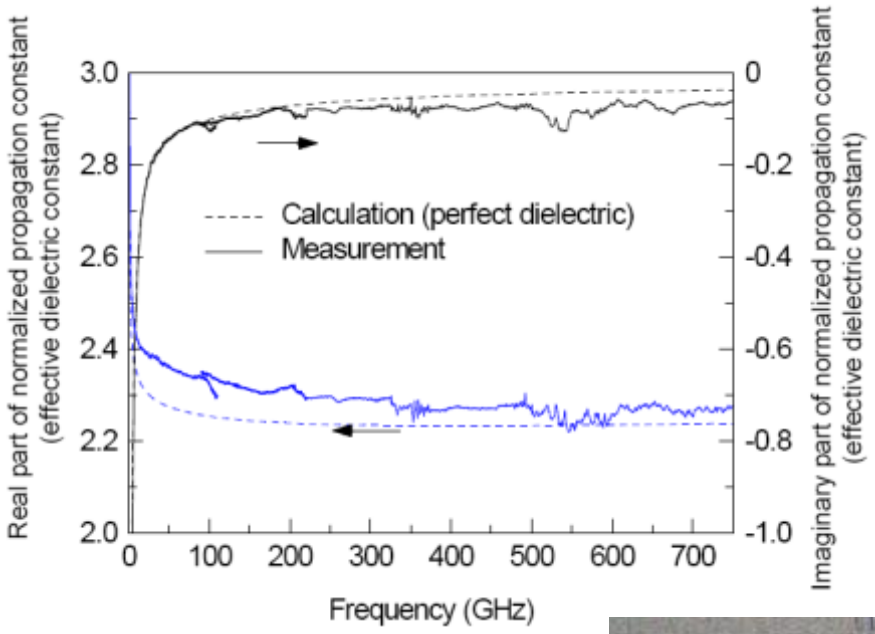
HP 8410

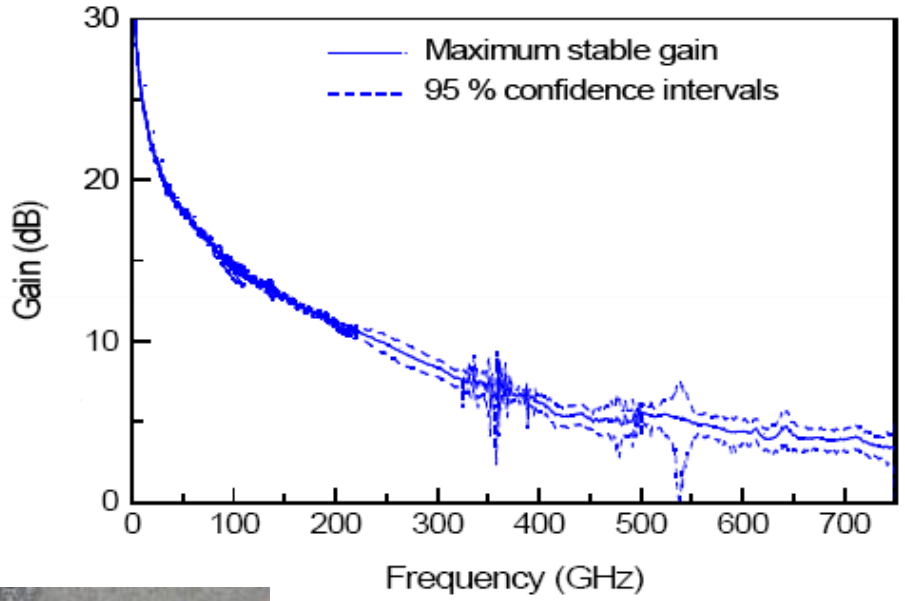
Wiltron 310

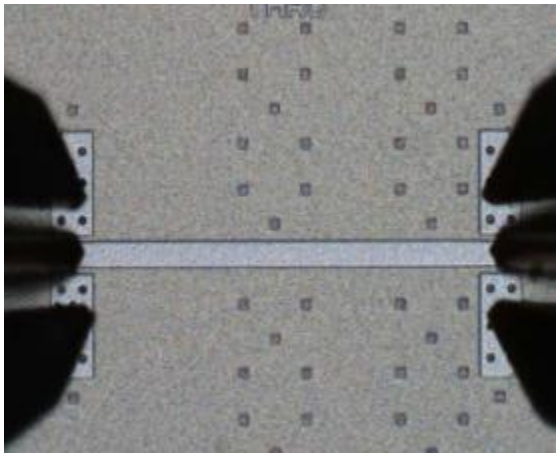
R&S

HP8410 Still Alive!

Today: On-Wafer Measurement







Williams, IMS-2014

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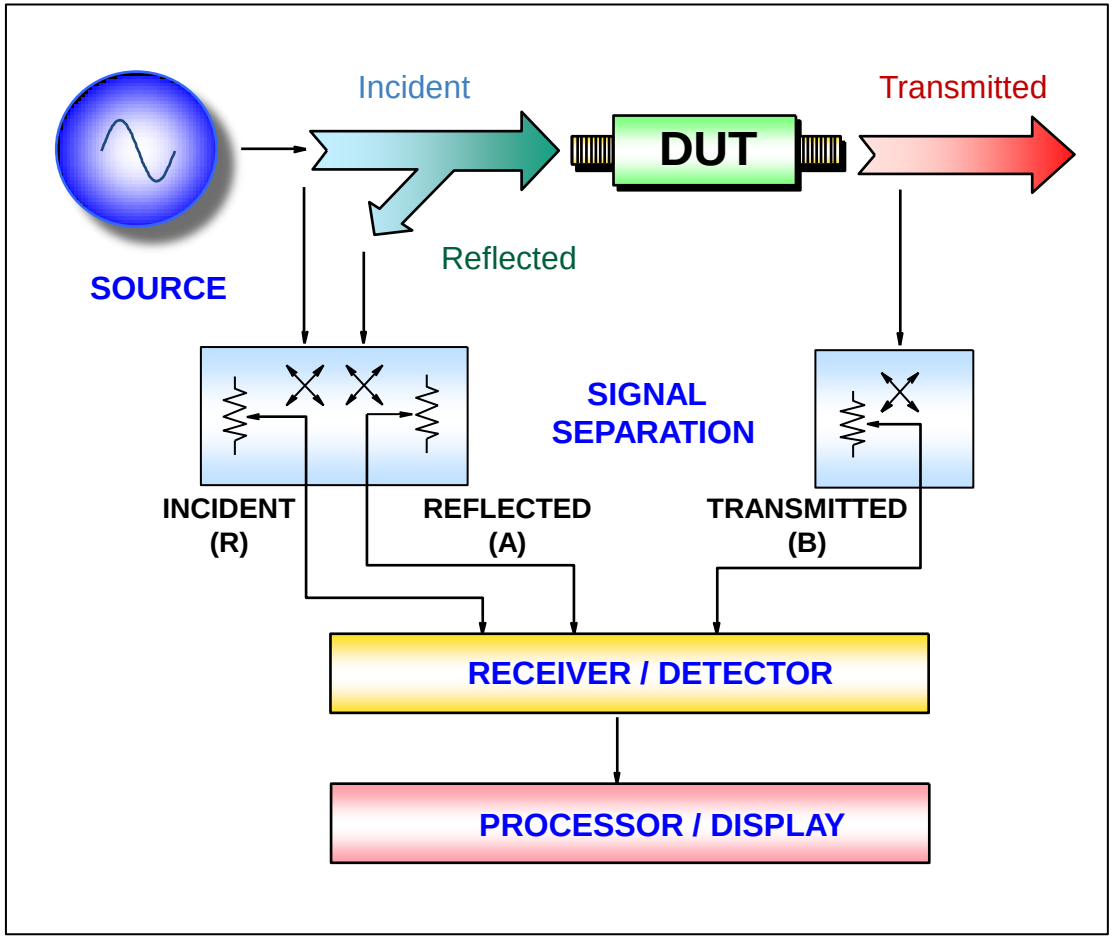
VNA Building Blocks



Picture source: D. Ballo Keysight

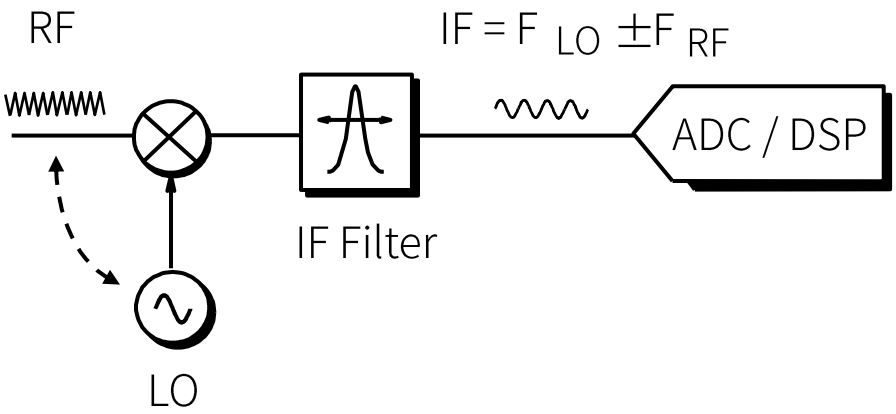
Receiver / Detectors

Diode

RF ~~~~~ — DC

Scalar
(no phase information)

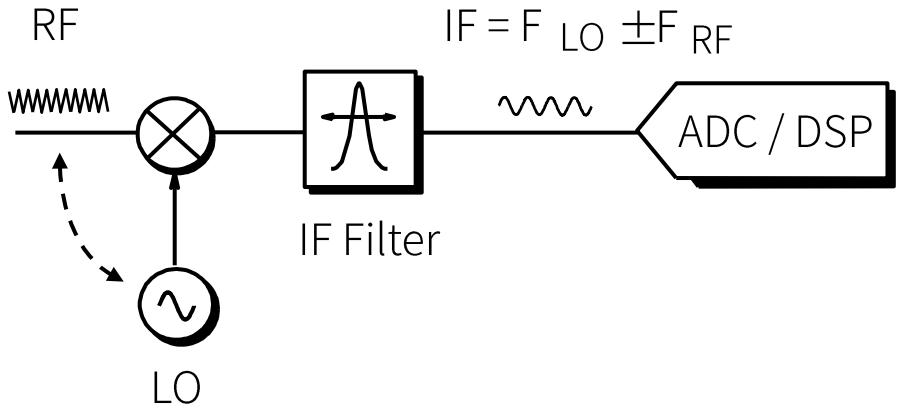
Tuned Receiver

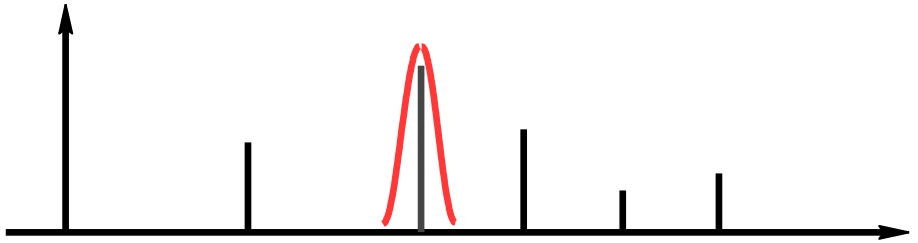


Vector
(magnitude and phase)

Picture source: D. Ballo Keysight

Narrowband Detection: Heterodyne Receiver

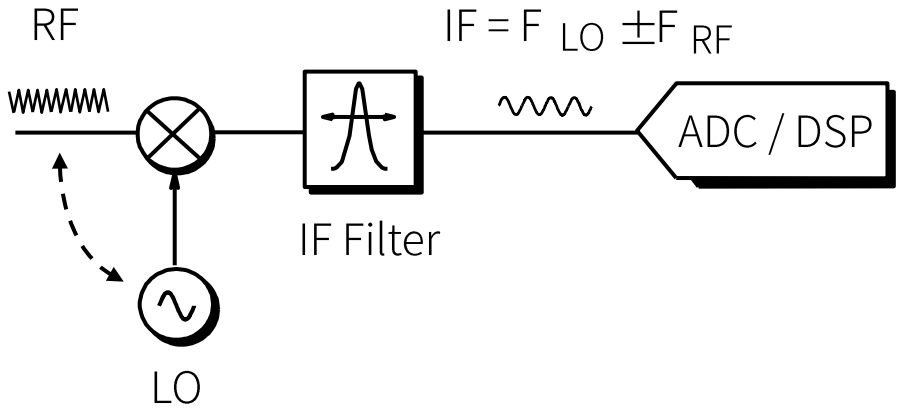


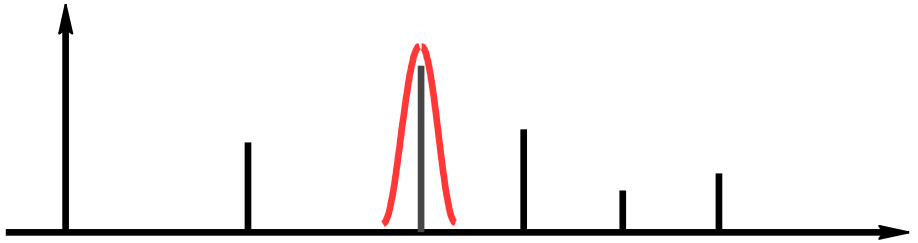


- Best sensitivity / dynamic range
- Provides harmonic / spurious signal rejection

Picture source: D. Ballo Keysight

Narrowband Detection: Heterodyne Receiver

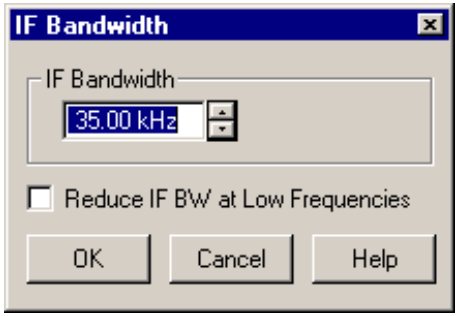




Trade off: noise floor and measurement speed

IF Bandwidth and Averaging

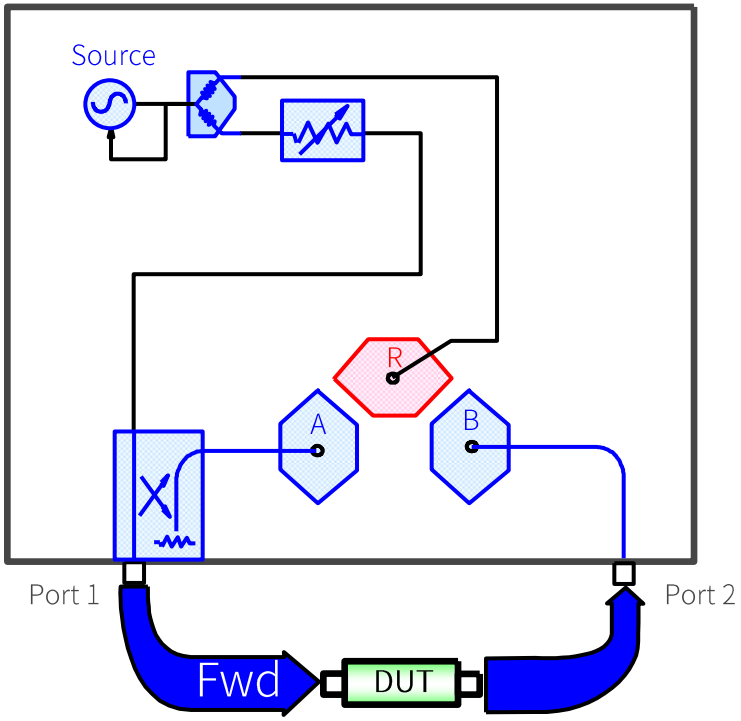
- Improve dynamic range by:
  - increasing power,
  - decreasing IF bandwidth, or
  - Averaging



- Recommended IFBW value 100 Hz
- Averaging : OFF

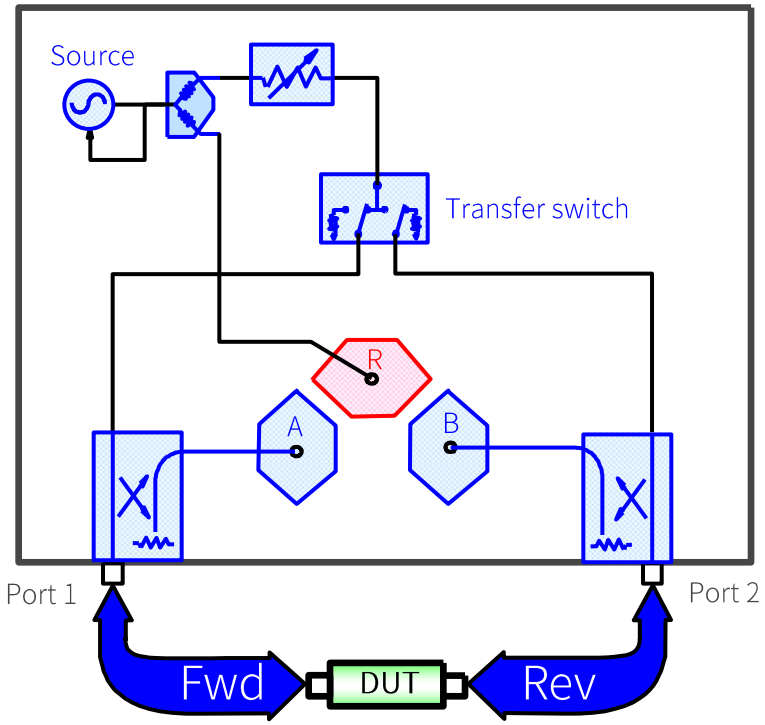
T/R Versus S-Parameter Test Sets

Transmission/Reflection Test Set



RF always comes out port 1
Port 2 is always receiver
Response, one-port cal available

S-Parameter Test Set

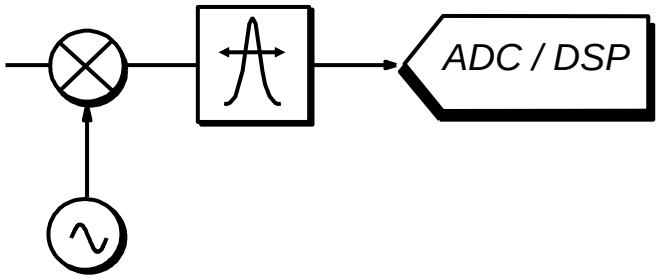


RF comes out port 1 or port 2
Forward and reverse measurements
Two-port calibration possible

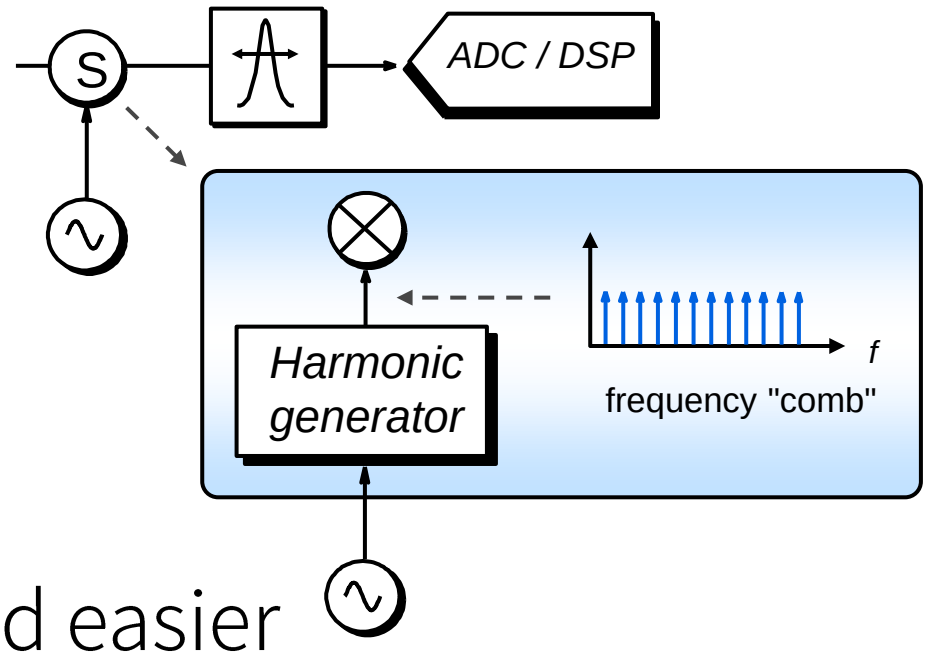
Picture source: D. Ballo Keysight

Front Ends: Mixers Versus Samplers

Mixer-based front end



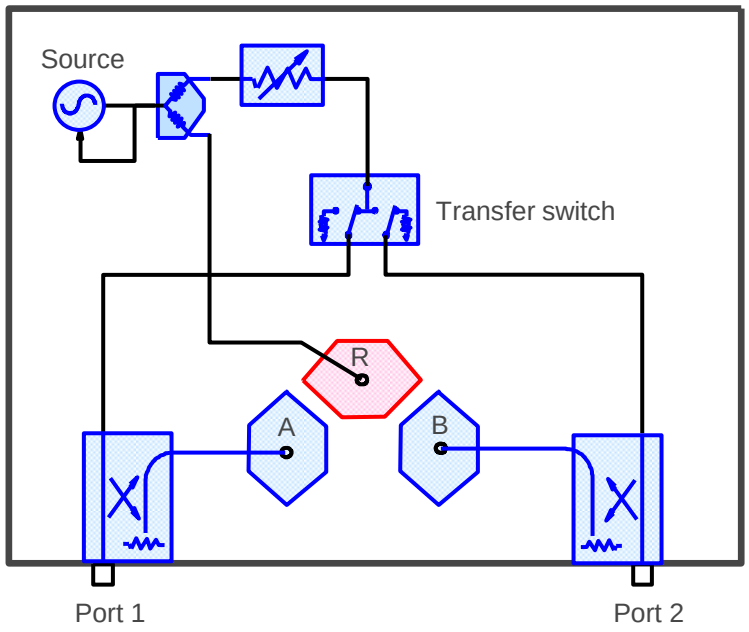
Sampler-based front end

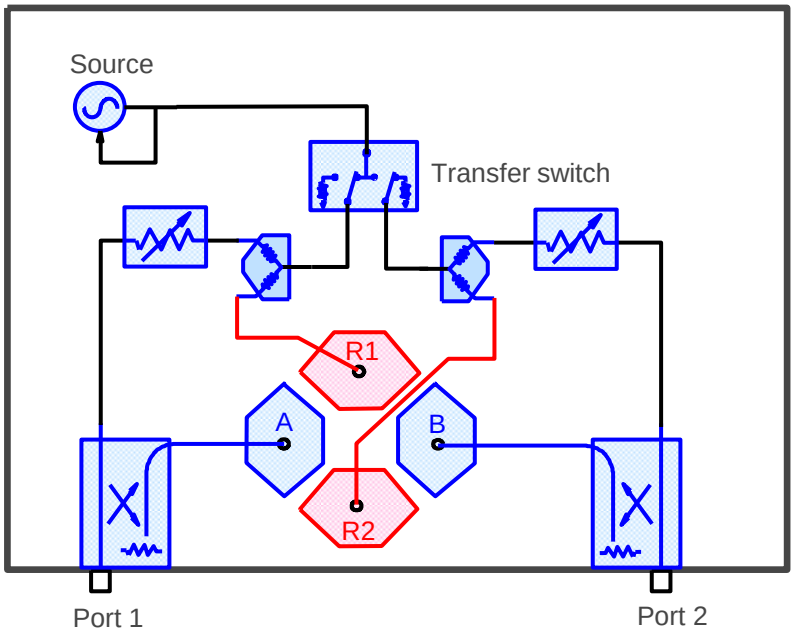


- Samplers: cheaper and easier
- Dynamic range?

Picture source: D. Ballo Keysight

Three vs. Four-Receiver Analyzers





- Reference Channel
  - Economy
  - Up to 20 GHz
- Double-Reflectometer
  - High-end
  - Up to THz

Picture source: D. Ballo Keysight

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What do we have today?

Instruments

KEYSIGHT TECHNOLOGIES

Anritsu envision:ensure

ROHDE&SCHWARZ

COPPER MOUNTAIN TECHNOLOGIES

NATIONAL INSTRUMENTS

Frequency Extenders

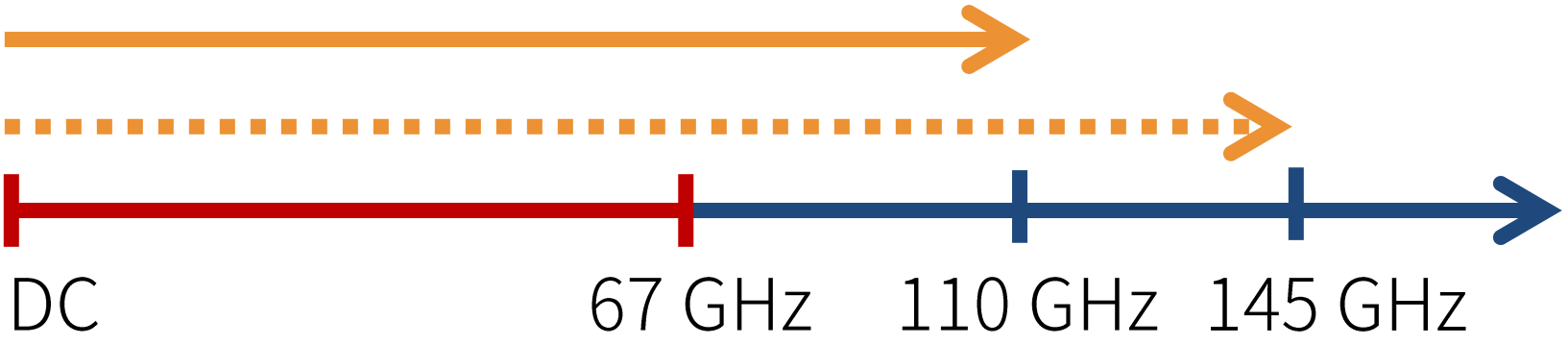
VDI

OML

Farran Technology
mmWave & Terahertz Solutions, Made Simple

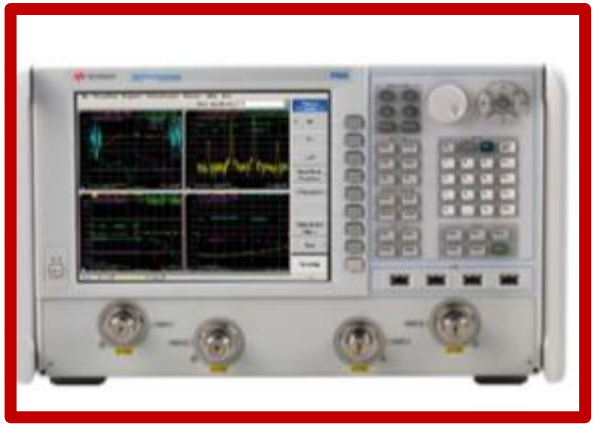
Frequency Range

- Baseband unit
  - From few Hz to 67 GHz
- Frequency extenders
  - From 67 GHz to 1.1 THz
  - Single sweep: from DC to 110 GHz (145 GHz)



Keysight (former Agilent)

KEYSIGHT TECHNOLOGIES



PNA-X

FiledFox PXI-VNA

ENA

PNA Family

	Model		Typical application	Frequency range
PNA Family *Reach for unrivaled excellence*		**N524xA PNA-X Series** *Most advanced and flexible VNA*	– Replace an entire rack of equipment with one instrument – Complete linear and nonlinear active device characterization	– 10 MHz to 8.5/13.5/26.5/ 43.5/50/67 GHz – Up to 1.1 THz with extenders
		**N522xA PNA Series** *High performance microwave VNA*	– Highest performance passive component analysis – Active components characterization – Metrology and cal lab	– 10 MHz to 13.5/26.5/ 43.5/50/67 GHz – Up to 1.1 THz with extenders
		**N523xA PNA-L Series** *Economy microwave VNA*	– Microwave S-parameter test – Signal integrity – Material measurements	– 300 kHz to 8.5/13.5/20 GHz – 10 MHz to 43.5/50 GHz

ENA Family

	Model		Typical application	Frequency range
ENA *Drive down the cost of test*		**E5072A ENA** *High performance RF VNA with configurable test set*	– RF amplifier test – BTS components – PIM measurements	– 30 kHz to 4.5/8.5 GHz
		**E5071C ENA** *High performance RF VNA*	– RF component test – Multiport module test – Material measurements – Signal integrity	– 9 kHz to 4.5/6.5/8.5 GHz – 300 kHz to 14/20 GHz
		**E5061B ENA** *LF-RF VNA with impedance analysis function* *Low cost RF VNA*	– LF component/circuit test – Component Z evaluation – RF component test – CATV component test	– 5 Hz to 3 GHz – 100 kHz to 1.5/3 GHz
		**E5063A ENA** Low-cost RF VNA for passive component test	– Antenna manufacturing test – RF passive component test – Material measurements – PCB manufacturing test	– 100 kHz to 4.5/8.5/18 GHz

ROHDE&SCHWARZ

High-end: ZVA

Midrange: ZVB 40GHz

Economy: ZVD 8.5GHz

Portable: ZVL 13.5GHz

Anritsu envision : ensure

VectorStar: ME7838

ShockLine: MS46xxx 40GHz

New Players

COPPER MOUNTAIN TECHNOLOGIES

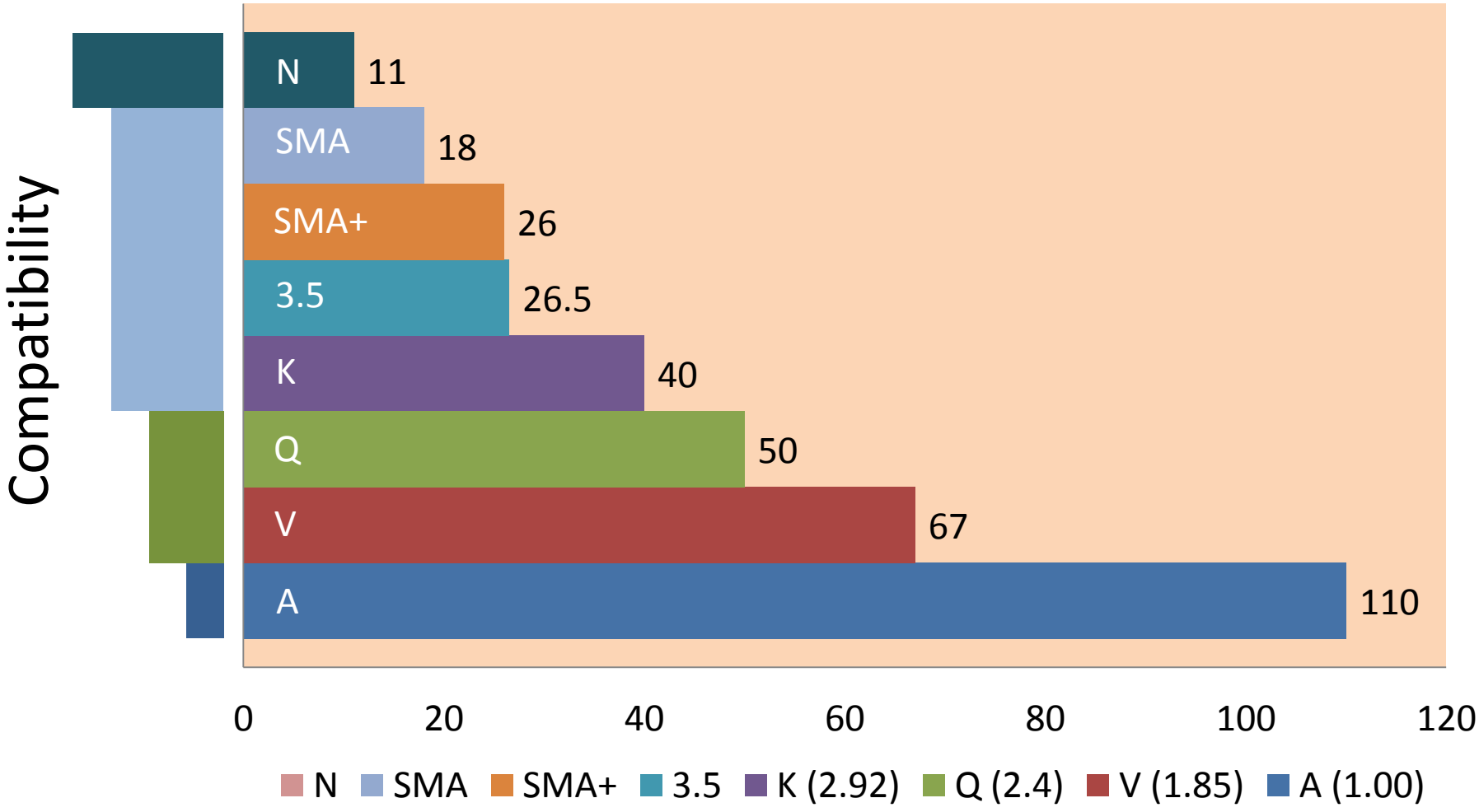
S5048 4.8GHz

P814 8.0GHz

NATIONAL INSTRUMENTS

PXIe-5632. 8.5GHz

Frequency Limits and Compatibility



Cable and Connectors

SMA

K (2.92 mm)

Q (2.4 mm)

V (1.85 mm)

A (1.00 m)

Cables

26 GHz

40 GHz

50 GHz

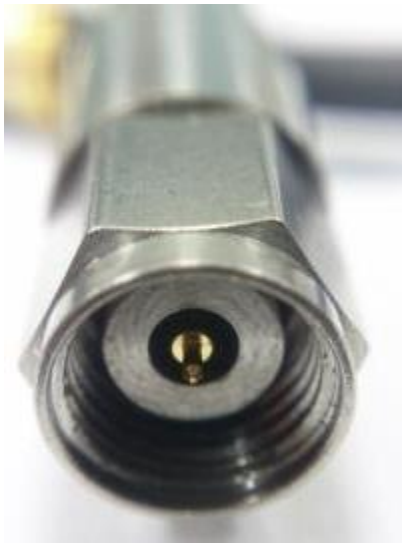
50 GHz

67 GHz

110 GHz

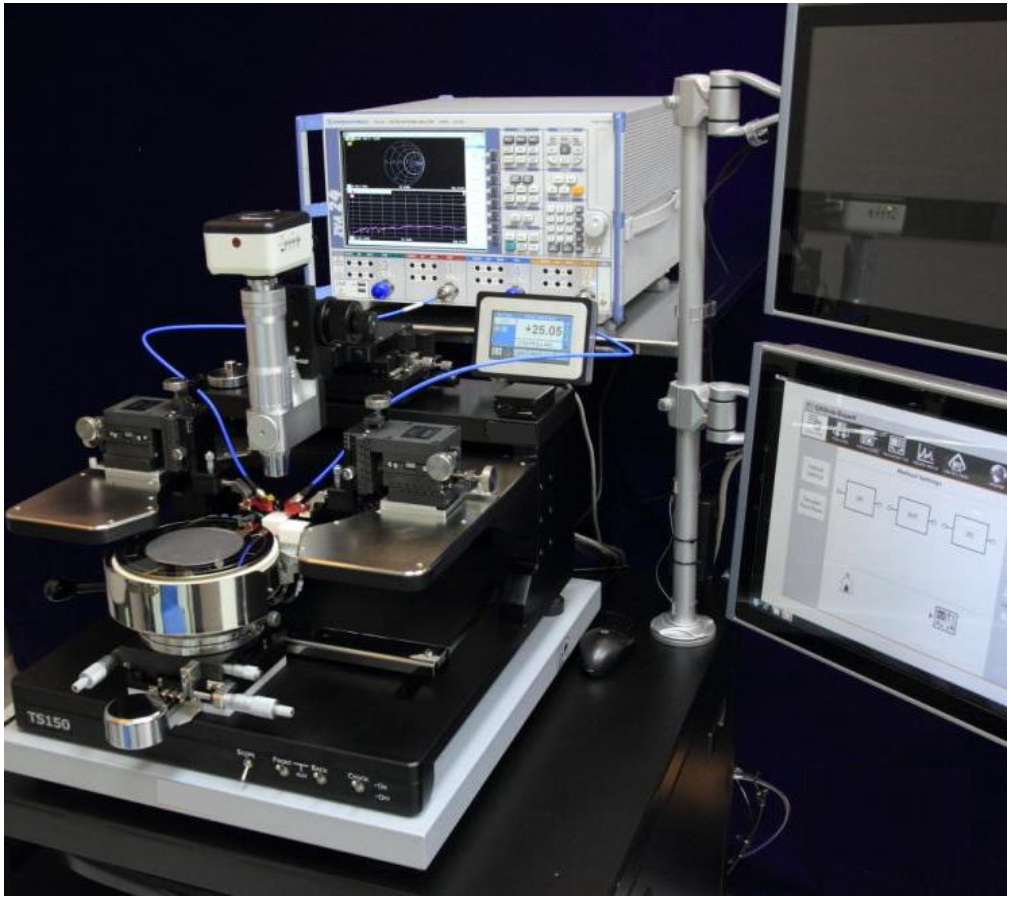
Comparison

Entry-level



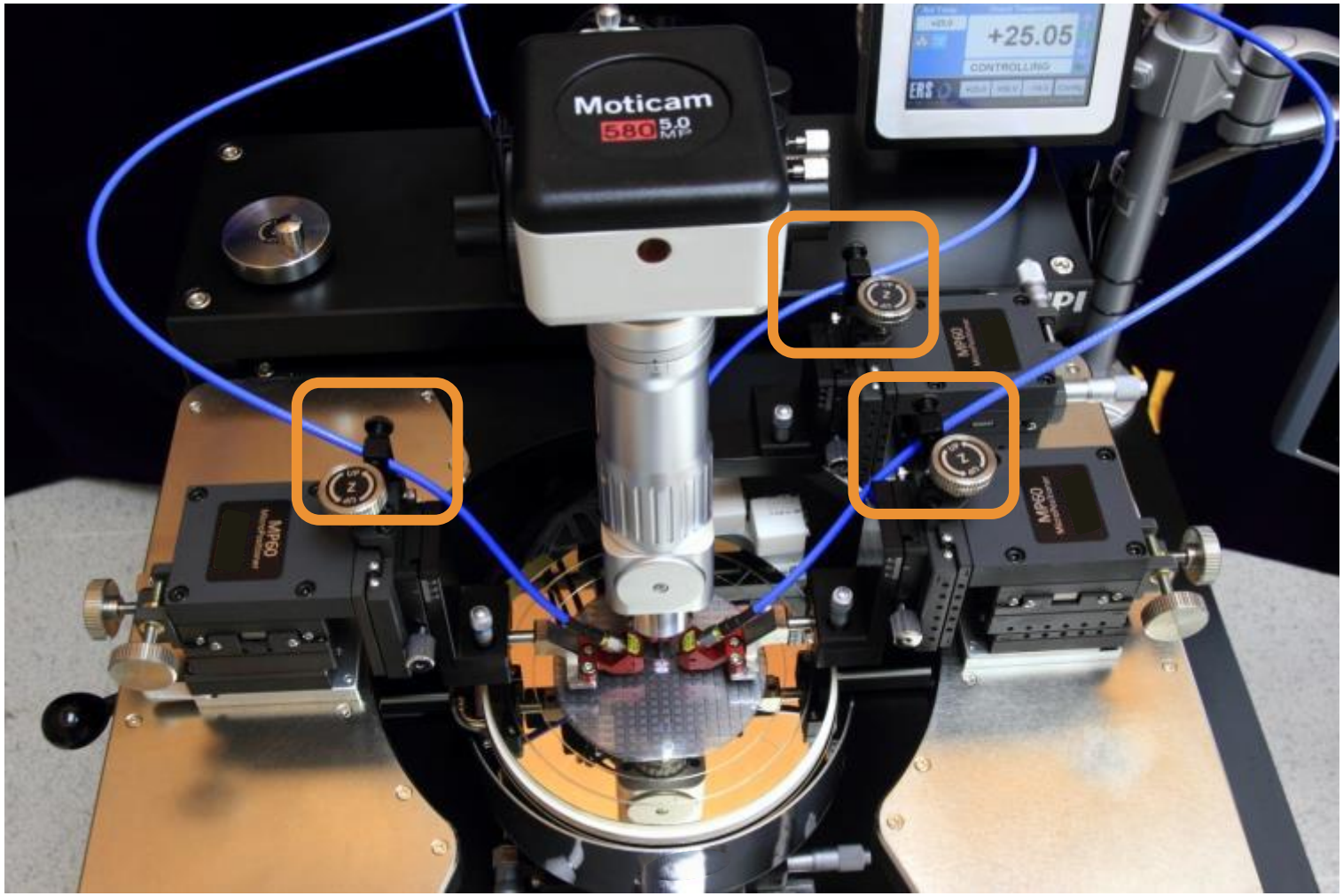
High-end

VNA Integration



- At the back
- Integrated shelf
- Optimized cable length: 80 cm

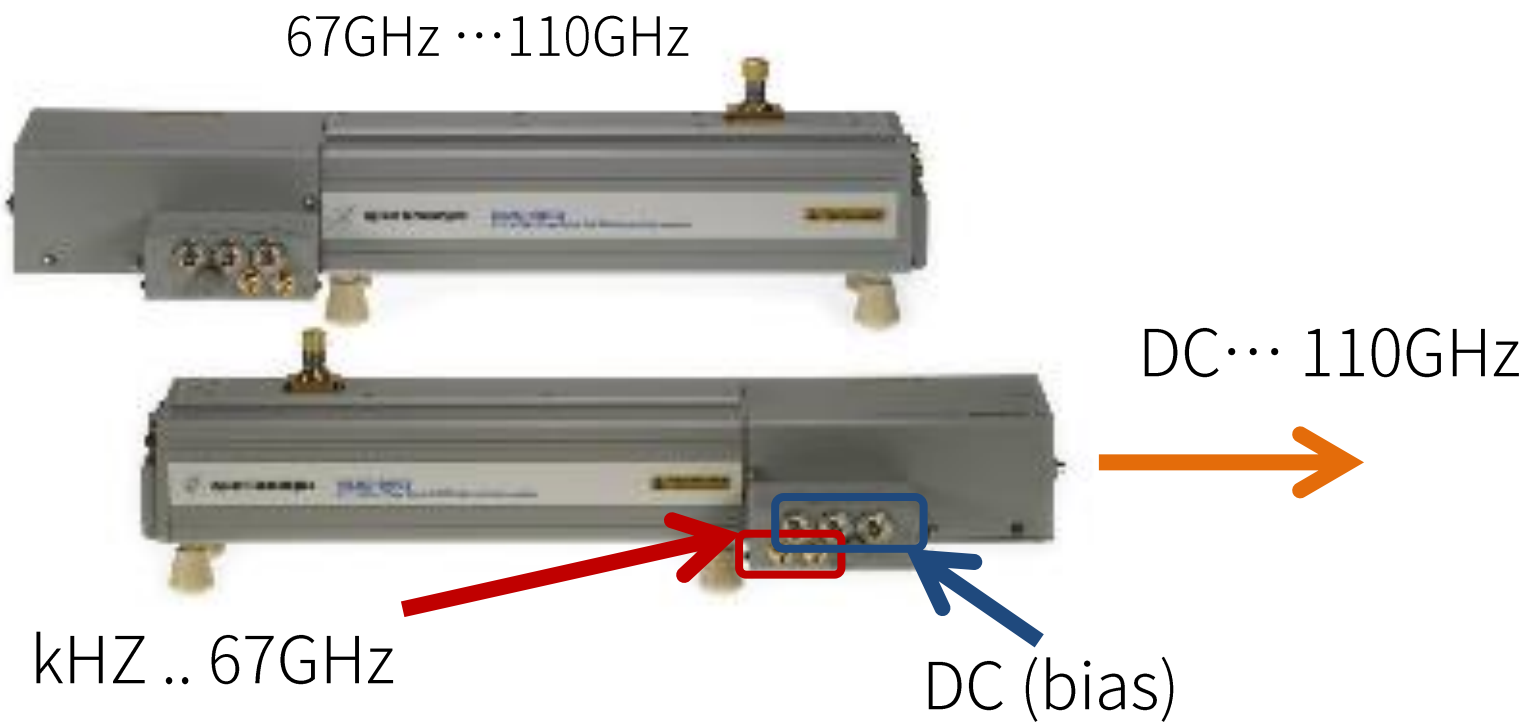
Cable Management on Positioner



Beyond 67 GHz below 110 GHz

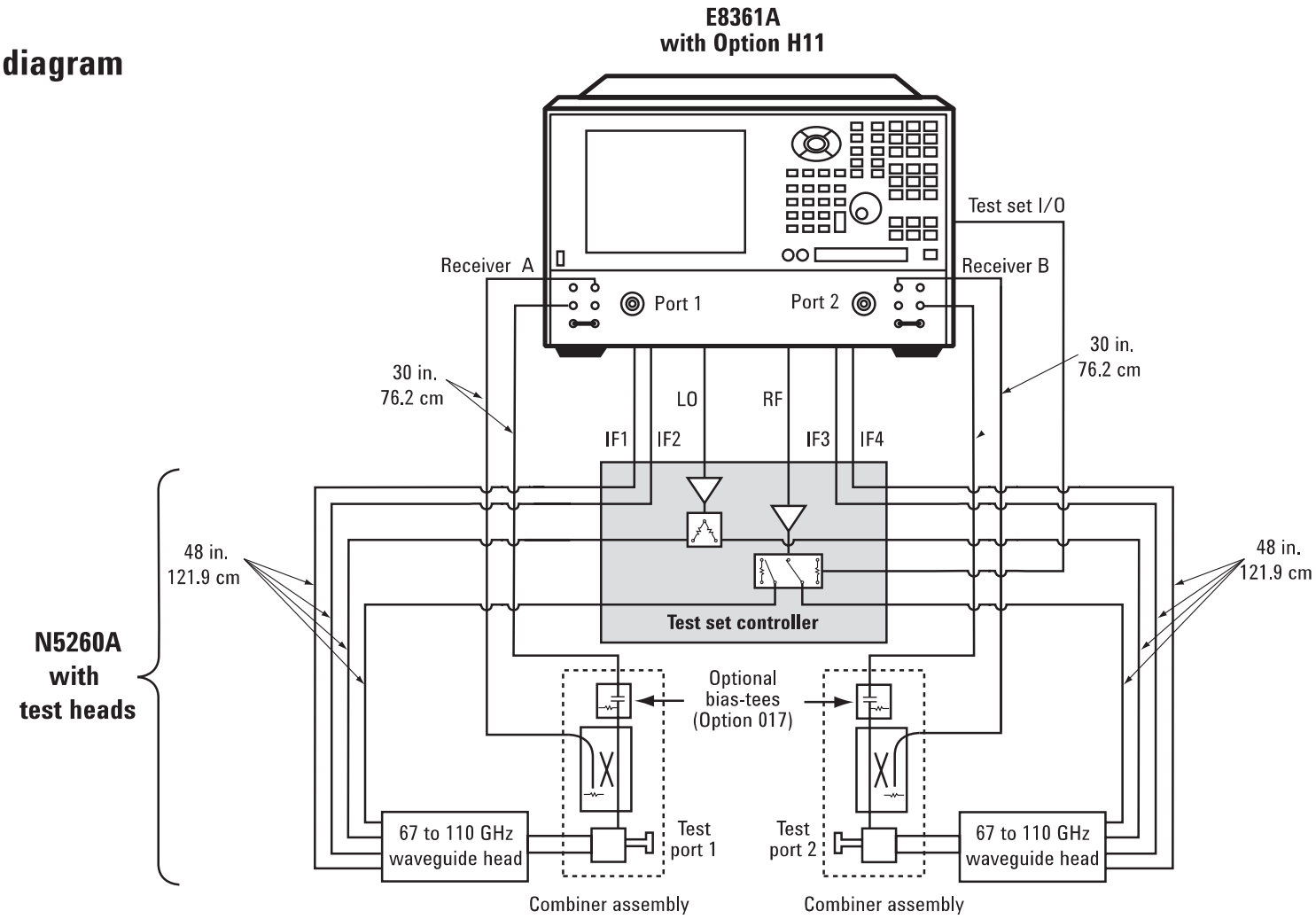
- External mm-wave heads (“extenders”)
  - From 67 GHz to 110 GHz
- Combiners
  - DC (bias source)
  - kHz…67GHz (baseband VNA)
  - 67GHz..110GHz (extenders)
- Broadband S-parameter measurement system

mm-Wave Heads



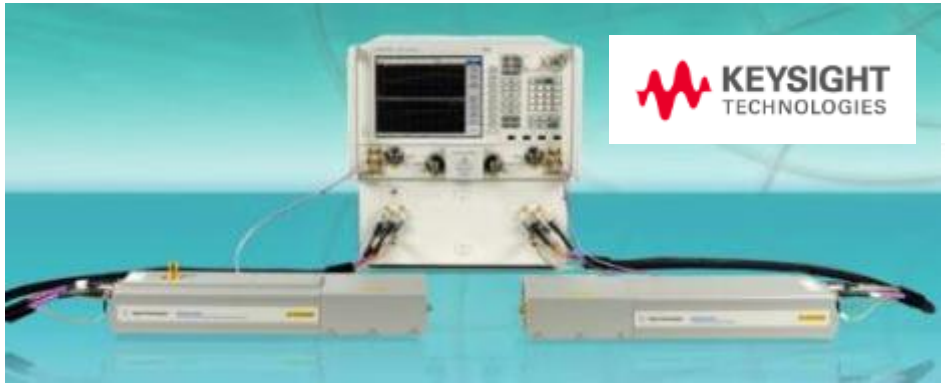
- IV/ S-Parameters measurements
- Device characterization for modeling

N5250A system block diagram

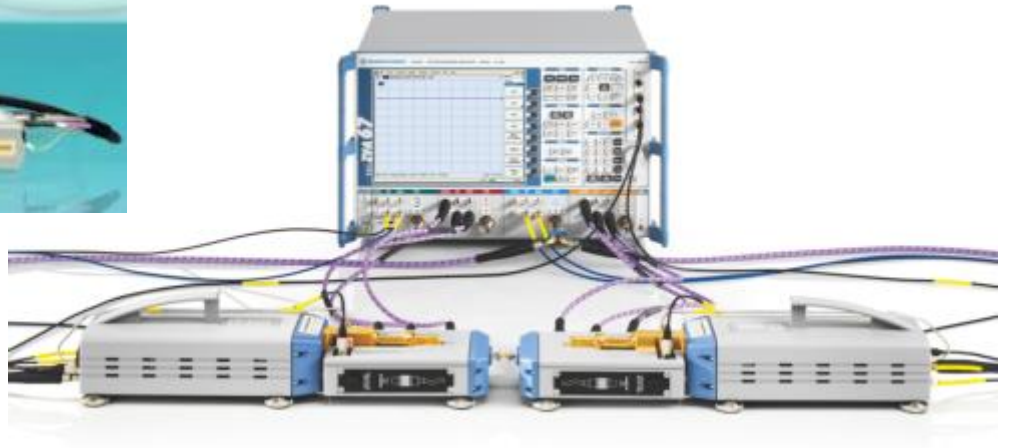


Picture source: Keysight

Broadband Systems



ROHDE&SCHWARZ



Anritsu envision : ensure

Key Wafer-Level Requirement

- mm-wave heads close to the DUT

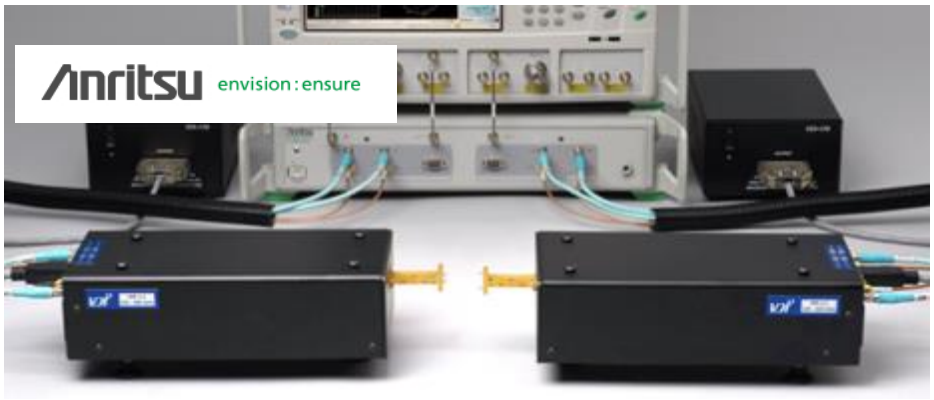
Banded Solutions

Band	WR15	WR12[1]	WR10[1]	WR08	WR06	WR05	WR03	WR02.2
Waveguide Interface								
Frequency (GHz)	50-75	60-90	75-110	90-140	110-170	140-220	220-325	325-500

- Dedicated mm-wave extender per band
- Our interest: from WR-10 and beyond

Banded Solutions: up to 1.1THz

VDI



Banded Solutions: up to 500GHz

OML

KEYSIGHT TECHNOLOGIES

Anritsu envision:ensure

ROHDE&SCHWARZ

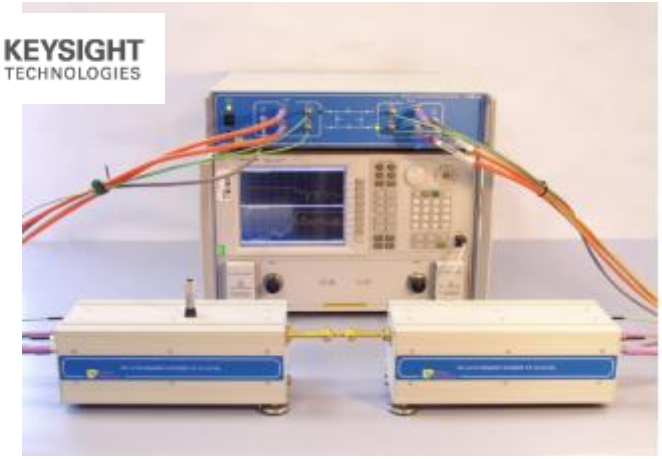
Banded Solutions: up to 500 GHz

ROHDE&SCHWARZ

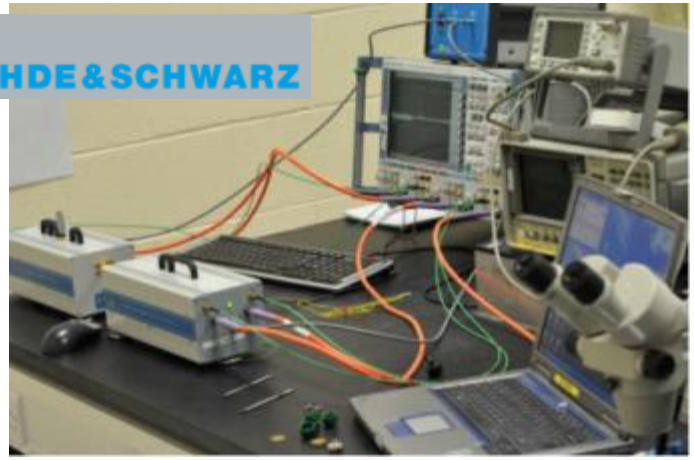
Banded Solutions: up to 325 GHz

Farran Technology
mmWave & Terahertz Solutions, Made Simple

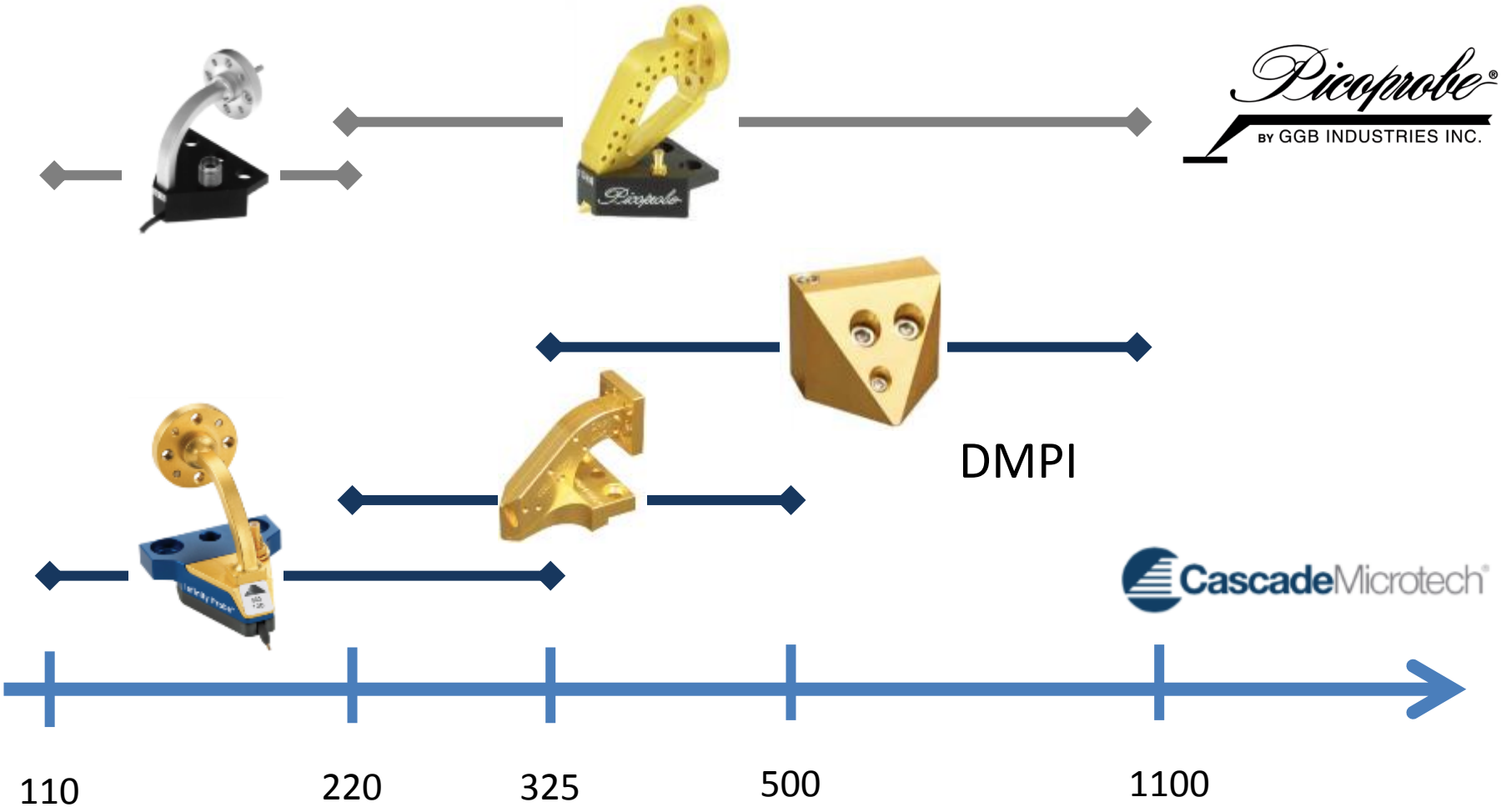
KEYSIGHT TECHNOLOGIES



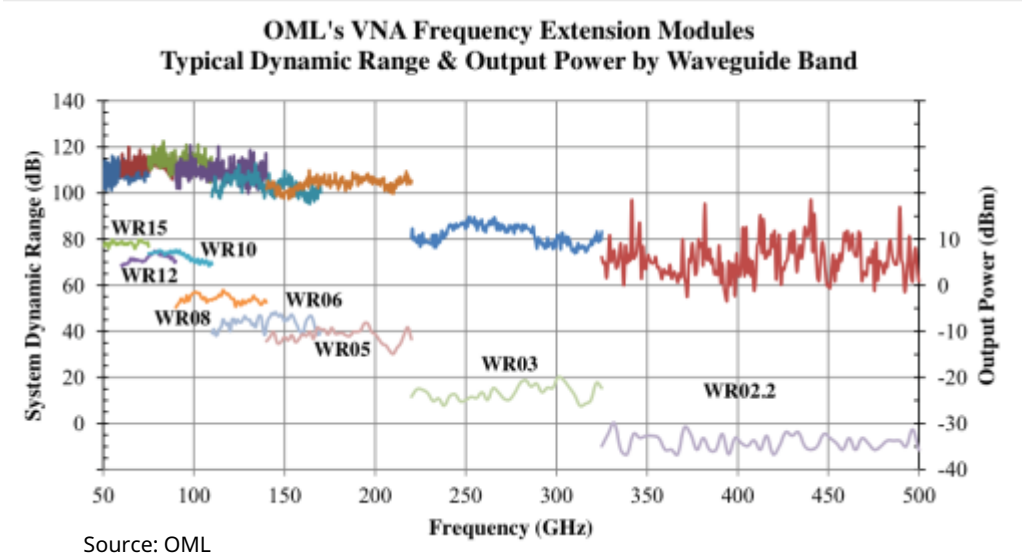
ROHDE&SCHWARZ



Banded Probes

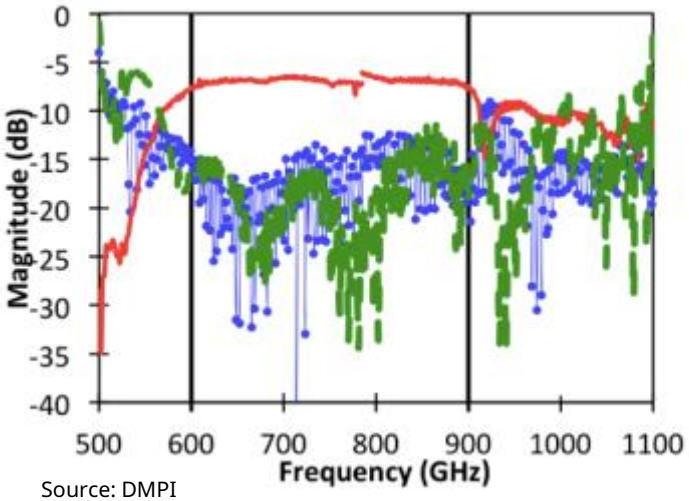


Banded Measurement Challenges



Source: OML

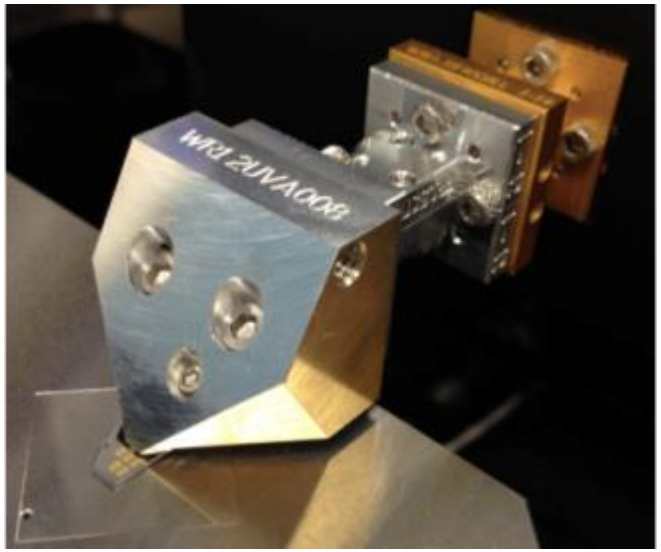
DMPI 1.1 THz Probe

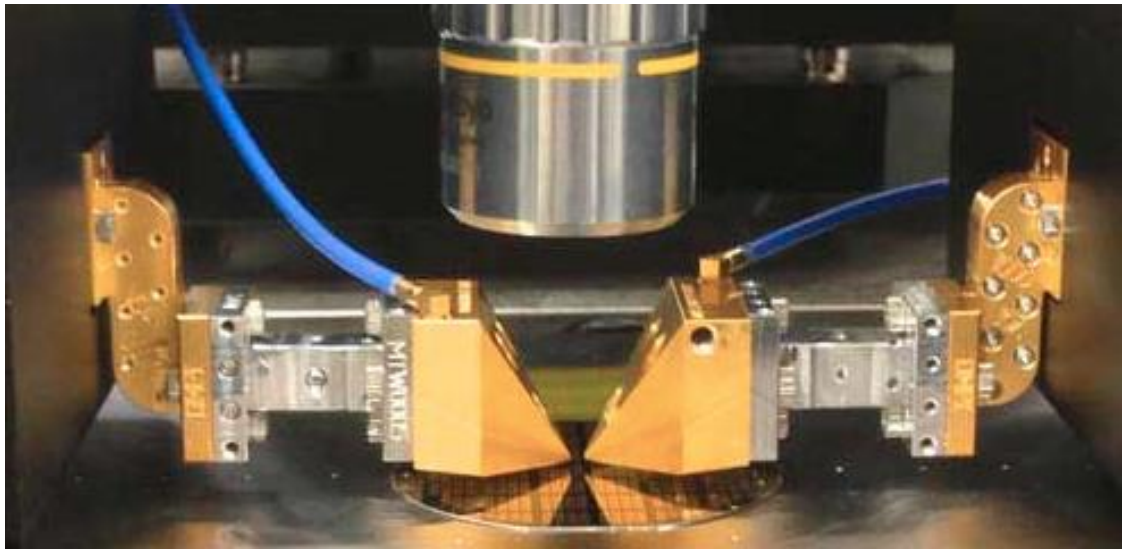


Source: DMPI

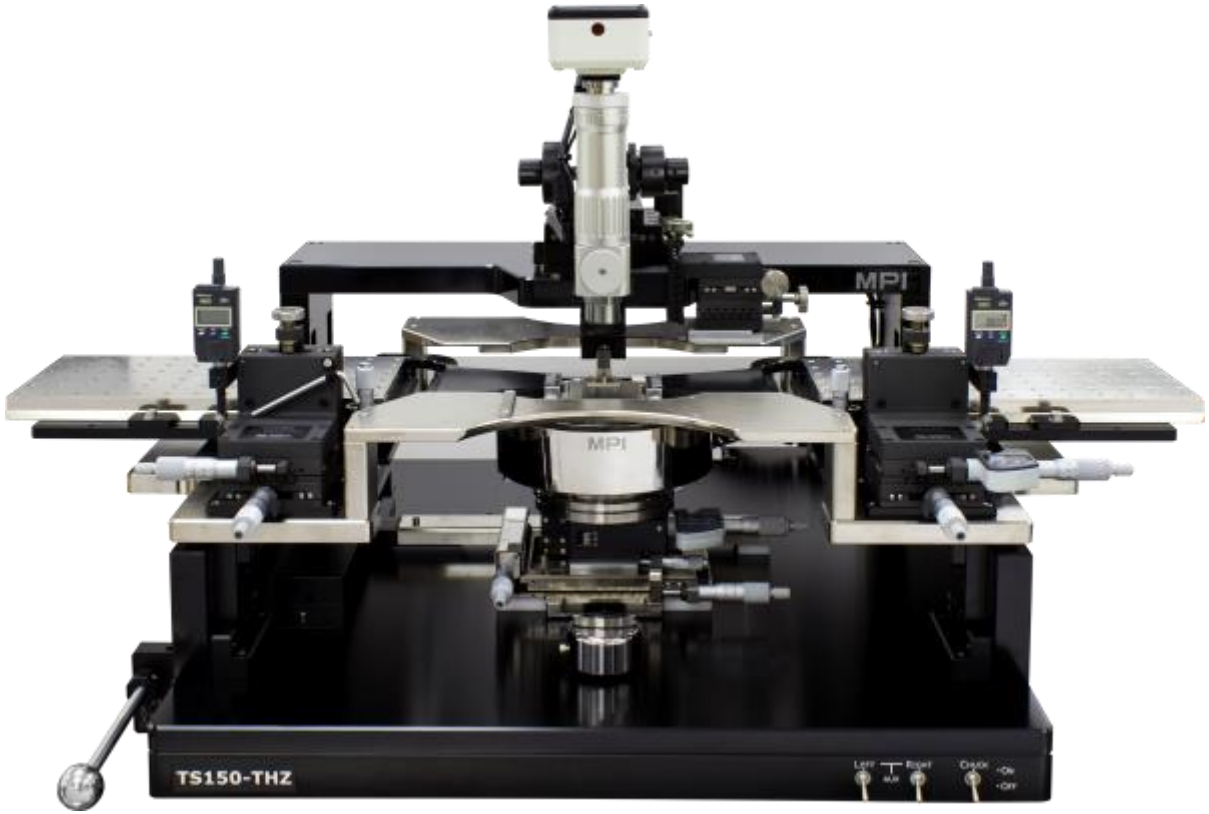
- VNA dynamic range decreases
- Waveguide losses increases
- Probe performance degrades

Probe Integration





Dedicated TS150-THZ System



MPI CORPORATION READY FOR THE TEST™

MPI TS150-THZ | 150 mm Manual Probe System

Industry's first explicitly designed probe system for accurate mmW and THz measurements

Microscope Mount and Movement
- Stable bridge for high quality optics
- 90° tilt for easy reconfiguration
- 50 x 50 mm linear XY movement

4-Port Bridge
- Two: in North and South
- Rectangular adjustments for RF positioners
- Designed as standard feature for DC biasing or 4-port RF
- For single DC or RF MicroPositioners

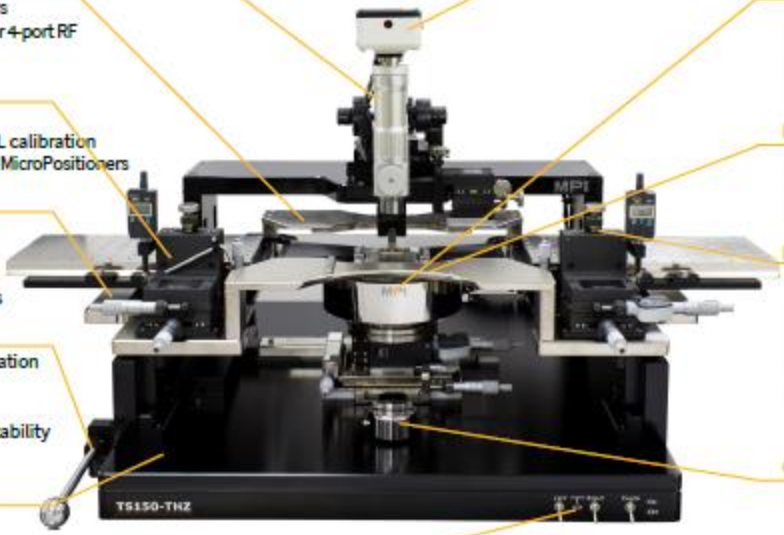
MicroPositioners
- Unique over-travel control option
- MP80-DX option for accurate multi-line TRL calibration
- Supports max. 2 bold down large area MP80 MicroPositioners

Probe Platen
- Single large probe platen in rigid design
- 4 probe platen supports for max. stability
- Designed especially to accomodate large positioners for mmW and THz applications

Unique Platen Lift
- Three discrete positions for contact, separation (300 µm) and safety loading 3 mm
- Safety lock function at loading position
- "Auto Contact" position with ±1 µm repeatability for consistent contact quality

Small Footprint
- Designed for bench top use
- Comes with vibration absorber base
- Low profile design for maximum usability
- Ideal for mmW, THz and load pull applications

Front Mounted Vacuum Control
- Easy access
- Clearly marked



Microscope and Optics Options
- Various optics options available
- Single tube MPI SZ10, MZ12 with up to 12x zoom and 95 mm working distance
- HDMI cameras, monitor user interface without computer

Modular Chucks
- Non-thermal or hot only chucks
- Dedicated RF or mmW designs
- Field upgradable for reduced cost of ownership
- Easy switch between center and small wafer size control

RF Calibration
- 2 auxiliary chucks for calibration substrates
- Built-in ceramic for accurate calibration
- 1 µm flatness for consistent contact quality

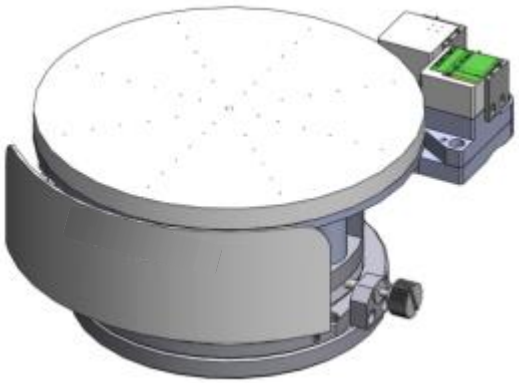
MP80 Integration Modules
- 2 options for waveguide or coax application
- Universal large area platforms for integrating various frequency extenders up to 1.1 THz
- Micrometer screws for fine waveguide probe leveling on the platforms
- Dove-tail interface for dedicated adaptations for easy setup and switching between different frequency bands

Chuck XYZ Stage Movement
- Unique puck controlled air bearing stage for quick single-handed operation
- Large vacuum base for max. stability
- 180 x 300 mm XY total stage movement
- Resolution < 1.0 µm (0.04 mils) @ 500 µm/rev
- 25 x 25 mm micrometer fine XY adjustment
- 10 mm fine Z, resolution < 1.0 µm (0.04 mils) @ 500 µm/rev, with digital indicator
- ±5° Theta fine adjustment
- Extra wide Y-range for easy loading

Available Options
- Various adaptations for different frequency extenders
- Vibration isolation table
- Table with integrated rack for thermal controller, computer and keyboard push tray
  - Dual monitor stand option
  - Instrument shelf option

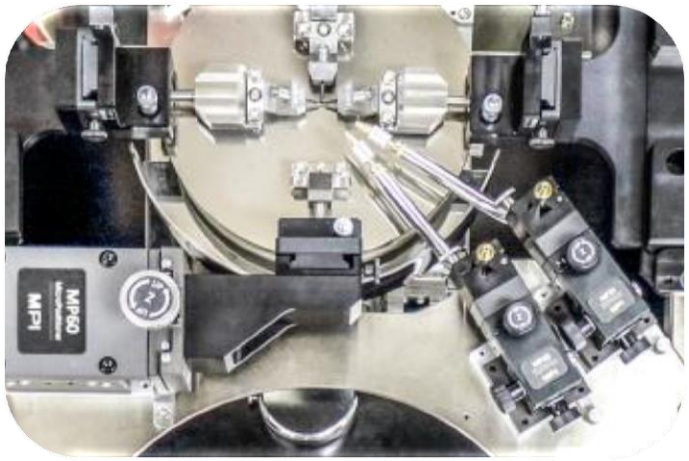
Designed for unsurpassed stability

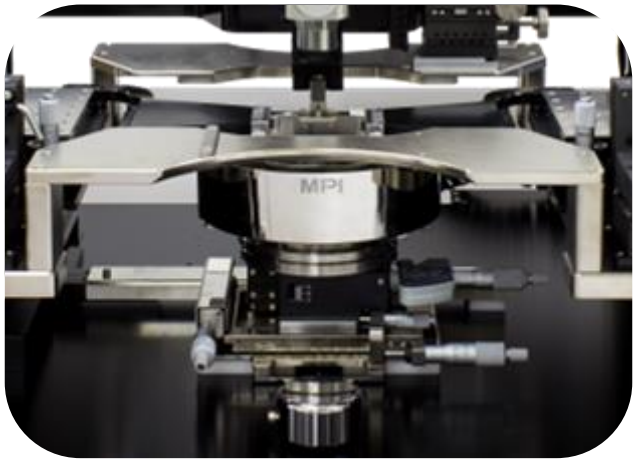
- Large area stainless steel probe platen
- Probe platen at lowest possible position
- No chuck elevation
- Ceramic chuck and AUX chucks



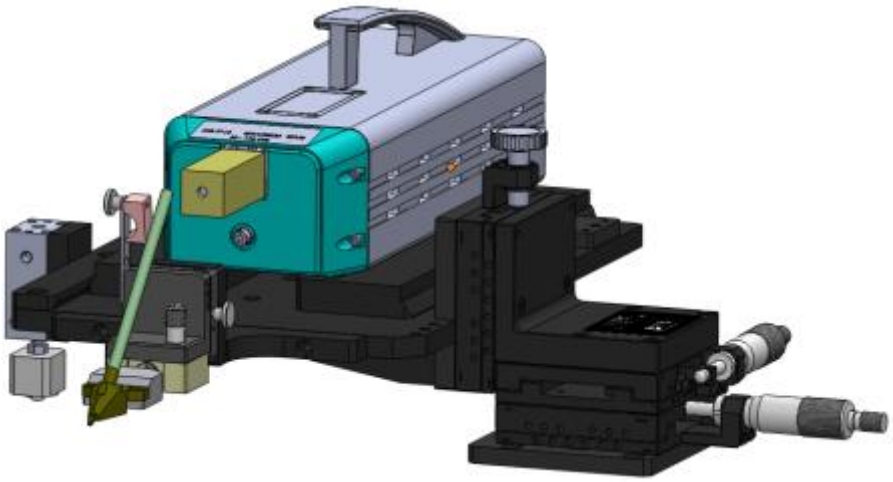
Dedicated Design for THz Application

- Support R&S and all other extenders:
  - up to 1.1THz
- 4-Port as part of the base system
- Fine Z chuck

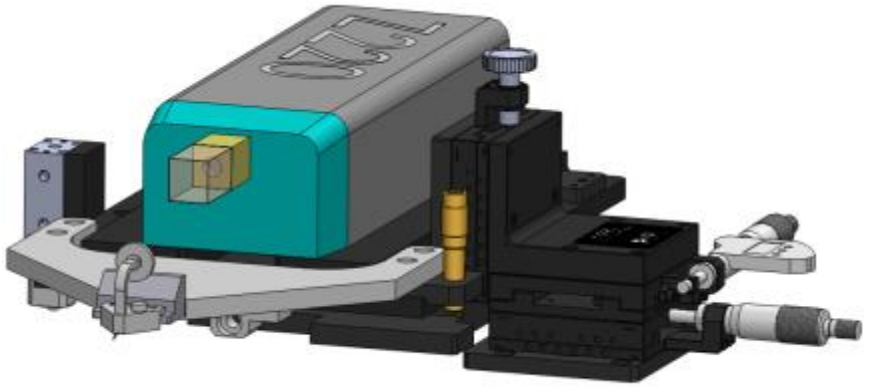




Different Extenders – Easy Reconfiguration

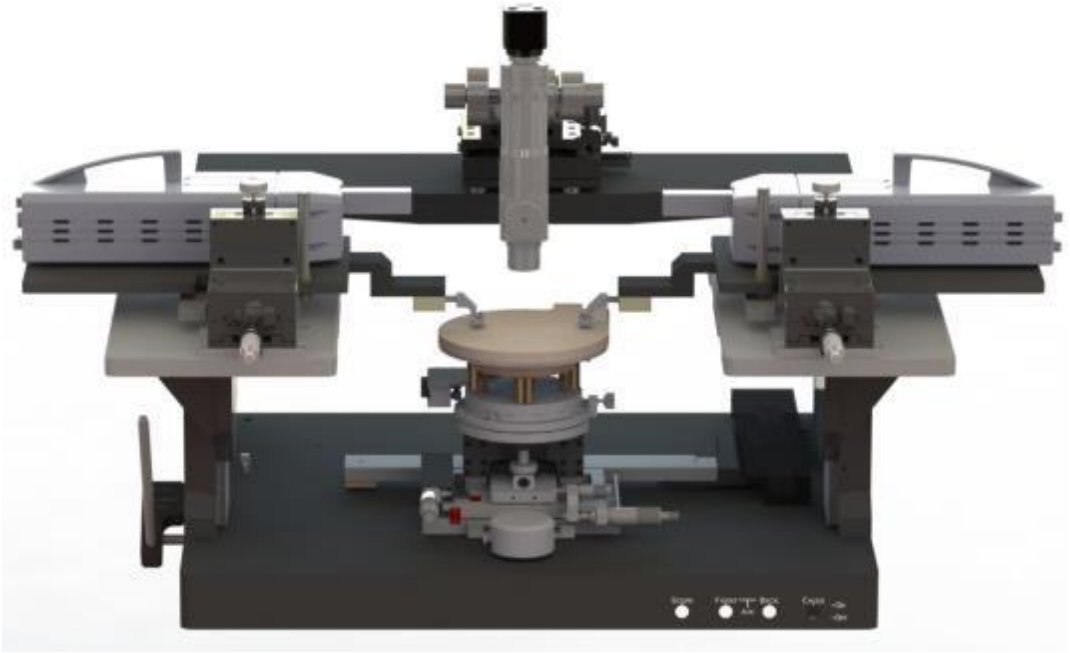


WR15, WR12, WR10



WR8

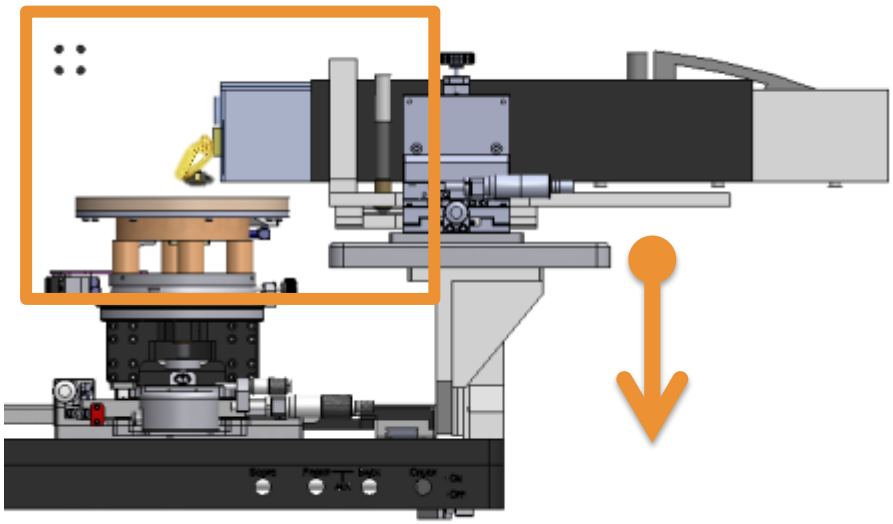
Banded 110 GHz···220 GHz



- Waveguide sections
  - Losses in are less critical
  - Probe performance is good

MPI

Banded THz Systems: 325+ GHz



- Losses and probe performance are critical
  - Direct probe mount
  - Unique low-down probe platen mechanism

THANK YOU
FOR YOUR ATTENTION

For more information, please visit:
www.mpi-corporation.com